



Cadence/Sigrity Stage 2 *Single-Stop SI/PI Solution for Chip-Package-Board*

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CDNLive
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Agenda

- Leading-edge analysis technology integrated with Allegro
- Industry-renowned workflow
- Complete SI/PI/EMI solutions

- ✓ Hybrid solver
- ✓ 3D EM field solver
- ✓ 3D thermal solver
- ✓ 3D adaptive meshing
- ✓ Impulse response generator
- ✓ Fast channel simulation
- ✓ Parallel computing
- ✓ Transistor-to-behavior model generator
- ✓ S-parameter → SPICE macro model
- ✓ Multi-physics simulation
- ✓ Thermal-RC extraction
- ✓ ...

Leading-edge analysis technology integrated with Allegro

Hybrid solver



US005504423A

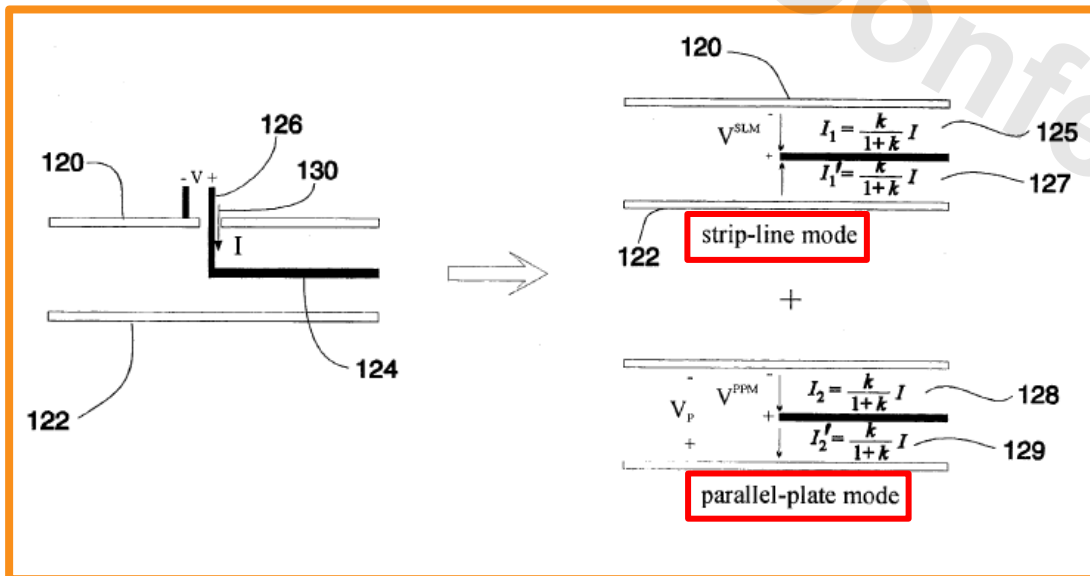
United States Patent [19]

[11] **Patent Number:** **5,504,423**

Fang

[45] **Date of Patent:** **Apr. 2, 1996**

METHOD FOR MODELING INTERACTIONS IN MULTILAYERED ELECTRONIC PACKAGING STRUCTURES



- The patented mode decomposition algorithm allows users to solve large package and board designs with good accuracy and performance
- Good for both time- and frequency- domain simulations

Leading-edge analysis technology integrated with Allegro

3D EM field solvers

Full-Wave (FW)

$$\nabla \times \vec{E} = -j\omega\mu\vec{H}$$

$$\nabla \times \vec{H} = j\omega\epsilon\vec{E} + \vec{J}$$

$$\nabla \cdot (\epsilon\vec{E}) = \rho$$

$$\nabla \cdot (\mu\vec{H}) = 0$$

Quasi-Static (QS)

$$\nabla \times \vec{E} = -j\omega\mu\vec{H}$$

$$\nabla \times \vec{H} = \vec{J}$$

$$\nabla \cdot (\epsilon\vec{E}) = \rho$$

$$\nabla \cdot (\mu\vec{H}) = 0$$

Static (S)

$$\nabla \times \vec{E} = 0$$

$$\nabla \times \vec{H} = \vec{J}$$

$$\nabla \cdot (\epsilon\vec{E}) = \rho$$

$$\nabla \cdot (\mu\vec{H}) = 0$$

S

RLGC

RC

Large

ELECTRICALLY

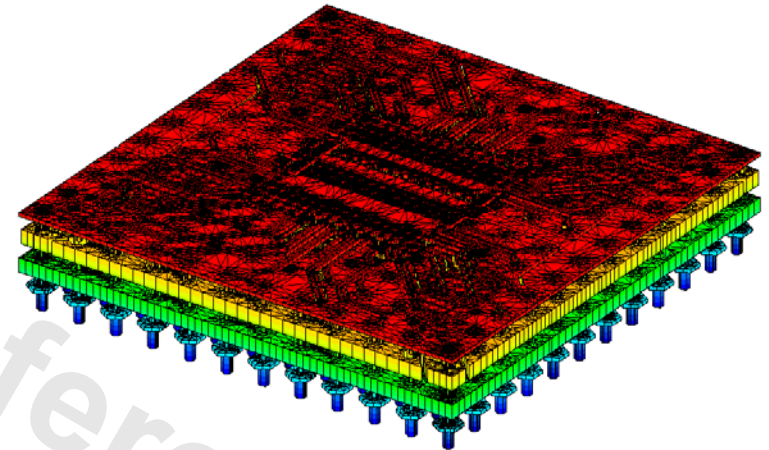
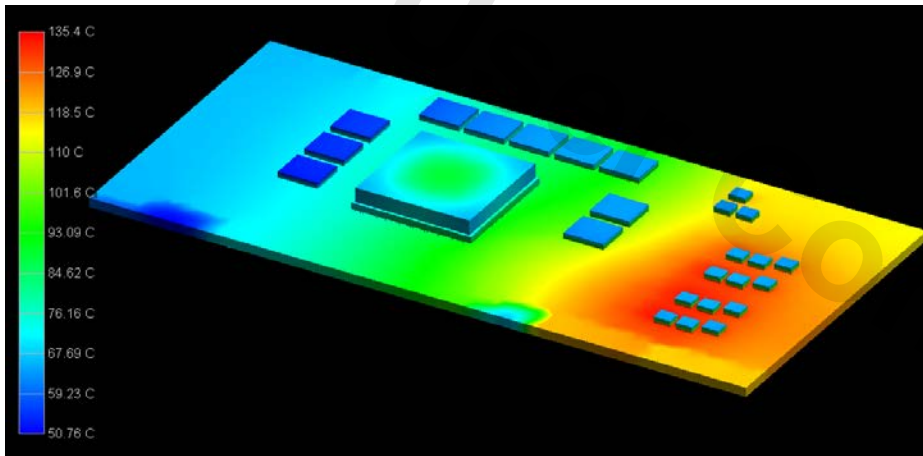
Small

- Explicit FEM solvers for FW, QS, and S for different application needs
- Low-frequency stabilizer in FW engine
- Latest Krylov model order reduction for fast and accurate frequency sweep
- Super memory-efficient matrix solver
- Latest multi-grid technologies to handle huge models

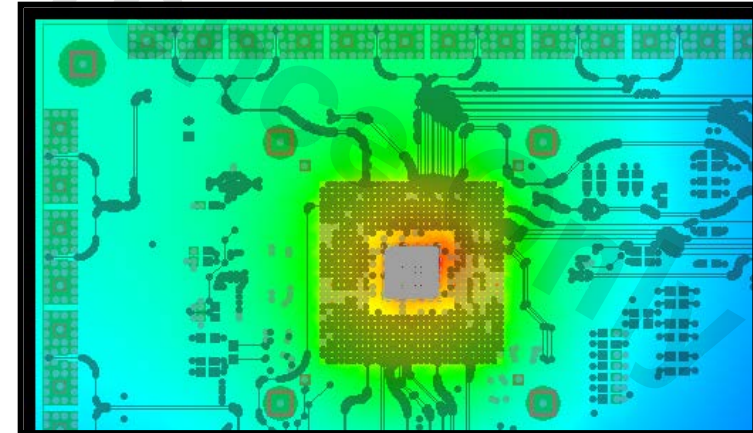
Leading-edge analysis technology integrated with Allegro

3D thermal solver

$$\frac{\partial}{\partial x} \left(k_x \frac{\partial T}{\partial x} \right) + \frac{\partial}{\partial y} \left(k_y \frac{\partial T}{\partial y} \right) + \frac{\partial}{\partial z} \left(k_z \frac{\partial T}{\partial z} \right) + Q = \rho c \frac{\partial T}{\partial t}$$

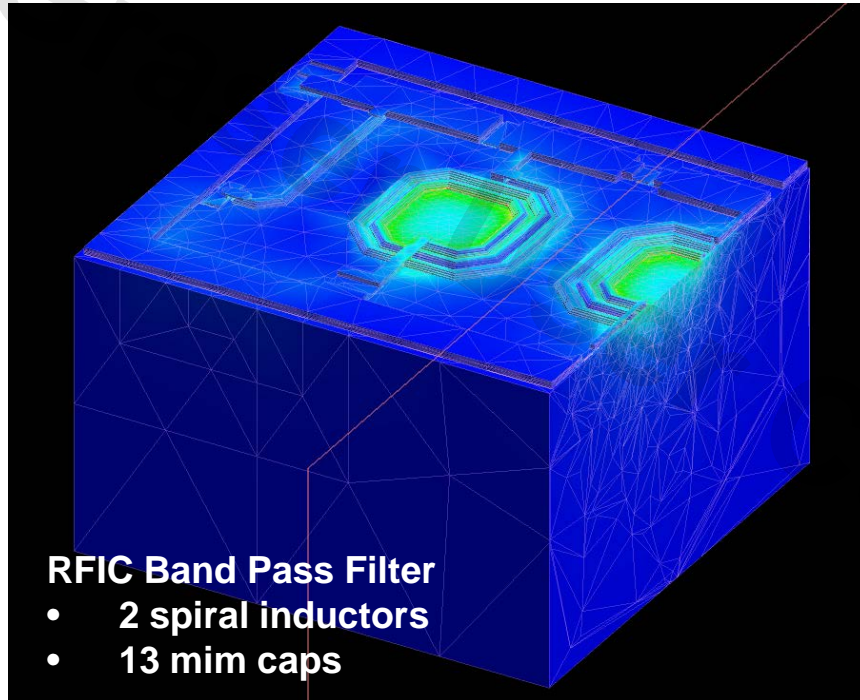


- Steady-state and transient heat conduction with convection and radiation BCs
- Finite element method with adaptive meshing, model order reduction, and multi-grid method solver

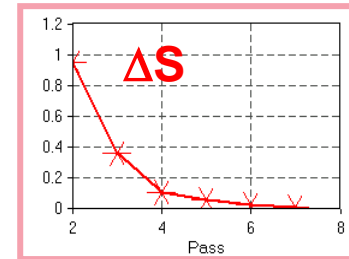


Leading-edge analysis technology integrated with Allegro

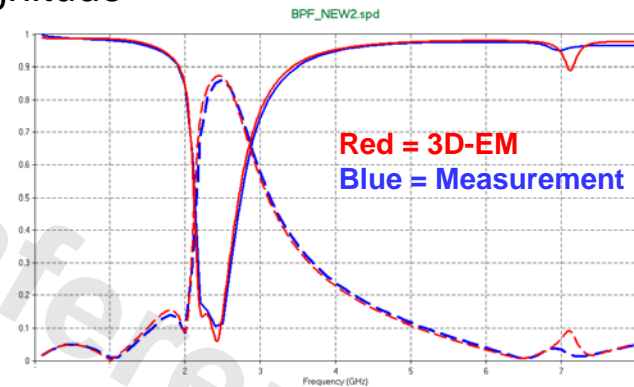
3D adaptive meshing for consistent accuracy



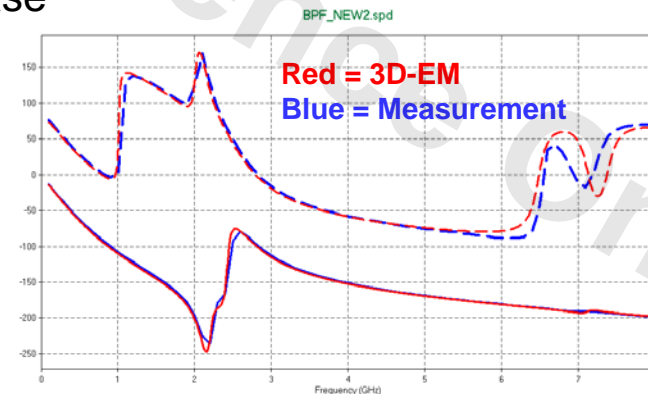
- Refine mesh based on solutions from previous mesh
- Elements with higher solution errors are refined
- Used in EM and thermal solvers



Magnitude



Phase



Leading-edge analysis technology integrated with Allegro

Patented impulse response generation

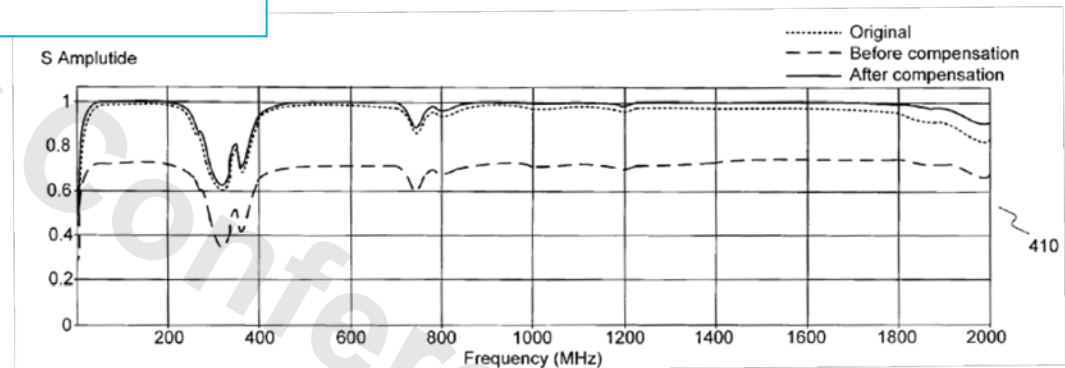
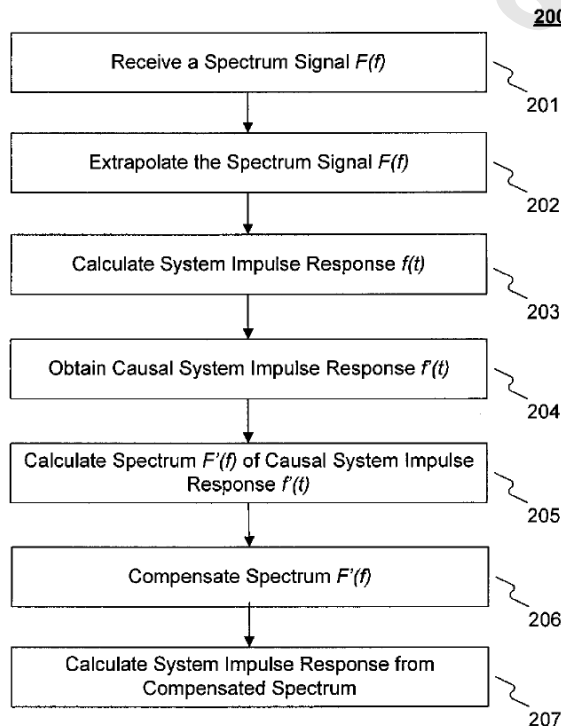


US008694568B2

(12) **United States Patent**
Li et al.

(10) **Patent No.:** US 8,694,568 B2
(45) **Date of Patent:** Apr. 8, 2014

(54) **METHOD FOR CALCULATING CAUSAL
IMPULSE RESPONSE FROM A
BAND-LIMITED SPECTRUM**

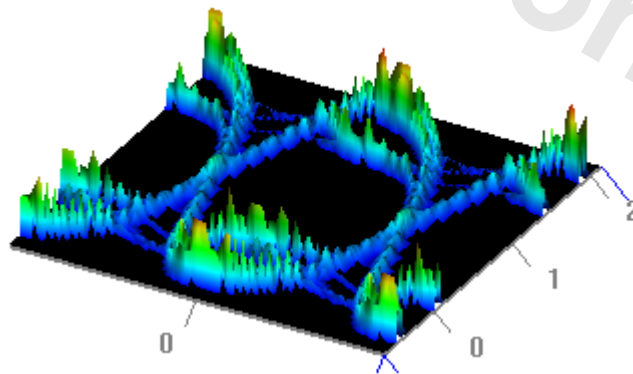
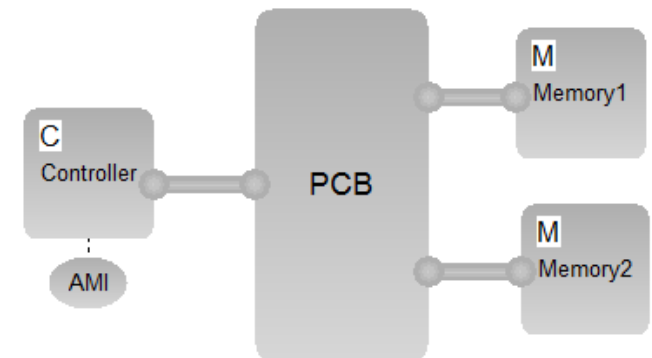


- The patented method generates a passive and casual time-domain impulse response from band-limited spectrum data
- Spectrum of the time-domain impulse response is almost identical to the original data
- This method is in time-domain simulations of S-parameters in Sigrity® tools

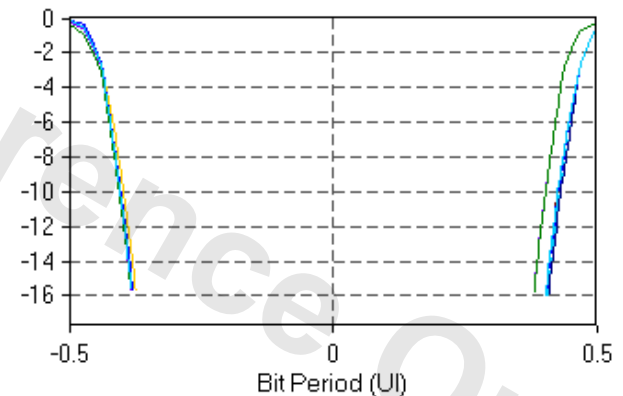
Leading-edge analysis technology integrated with Allegro

Fast channel simulation for DDR4

- Fast SSN channel characterization
 - Ability to run **millions of bits**
- Jitter and noise injection
- AMI modeling for adaptive equalization
- Bathtub curve and eye generation
- DQ mask and BER measurement and report



Log BER



4.2.2 Worst Case Summary

| Measurement | Vcent_DQ (V) | DQ Compliance Mask | Min Jitter_margin (ps) | Min Noise_margin (mv) | [Max] tDQS2DQ (ps) | [Max] tDQS2DQ_BC (ps) | Max tDQ2DQ (ps) | Min VIH_L_AC (mV) | Min TdIPW (ps) | Min SlewRate_Mask (V/ns) | Max SlewRate_Mask (V/ns) | Min SlewRate_AC_Swing (V/ns) | Max SlewRate_AC_Swing (V/ns) |
|----------------------|--------------|--------------------|------------------------|-----------------------|---------------------|-----------------------|-----------------------------|---------------------|---------------------|--------------------------|--------------------------|------------------------------|------------------------------|
| Worst Value | | | 134.923 | 166.916 | -33.1392 | 6.60106 | 13.2021 | 469.832 | 396.02 | 3.20676 | 4.32314 | 3.05877 | 4.2416 |
| Rx Signal (Waveform) | | | DQ6 | DQ4 | DQ7 | DQ3 | All Signals | DQ4 | DQ6 | DQ6 | DQ4 | DQ6 | DQ4 |

Leading-edge analysis technology integrated with Allegro

Parallel computing

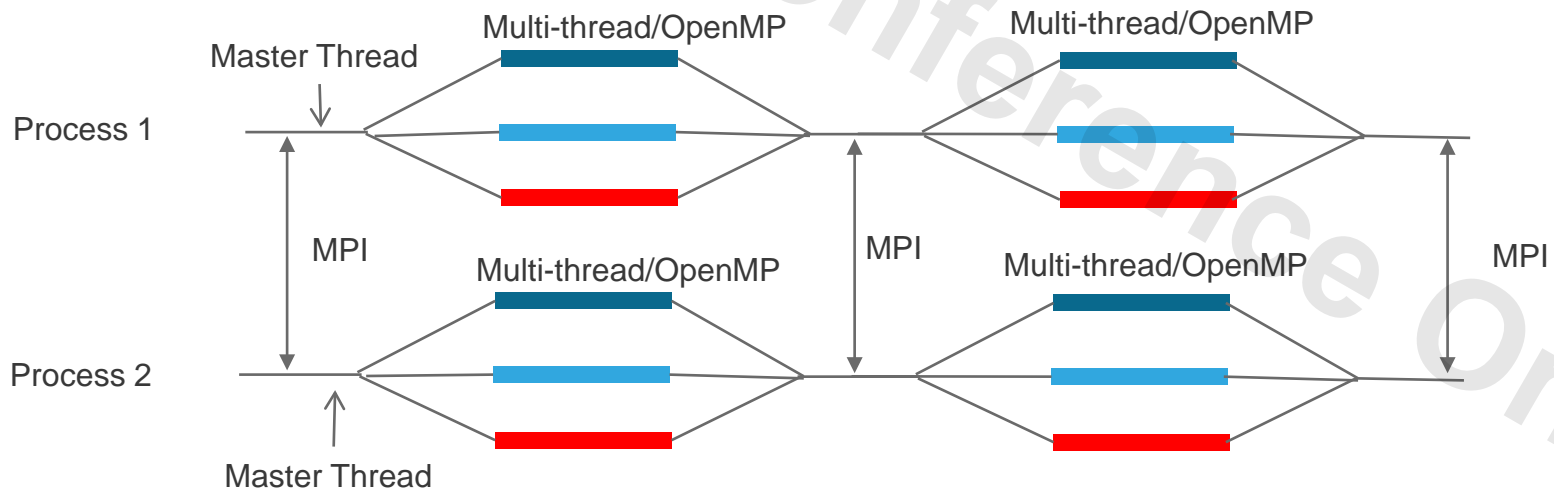
- **Threads model**

- Multiple concurrent thread
- OpenMP

- **Distributed**

- Message Passing Interface (MPI)

- Distributed computing with MPI and OpenMP to leverage server farm capacity



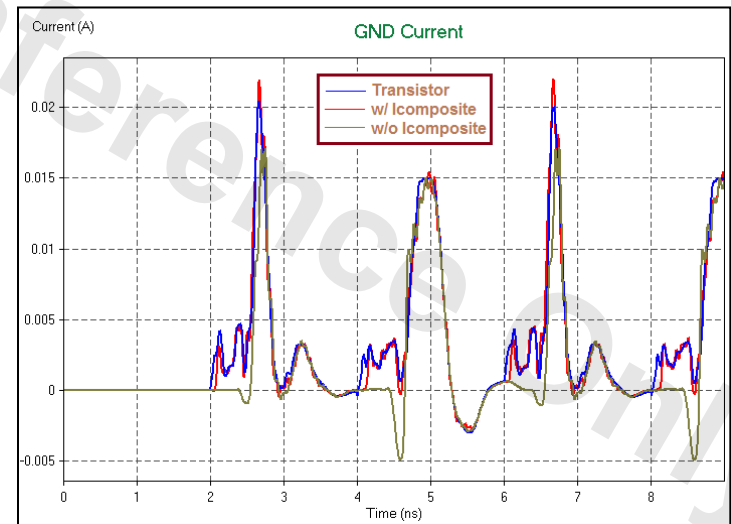
Leading-edge analysis technology integrated with Allegro

Transistor models → behavior model

- Industry's most advanced tool for converting transistor models to **power-aware** IBIS
- Convenient GUI verifies conversion accuracy
- Simulation speed-up makes full bus simulations practical; this would otherwise take weeks
- Optional IBIS plus model provides additional level of accuracy



Built-in simulation check compares transistor to IBIS

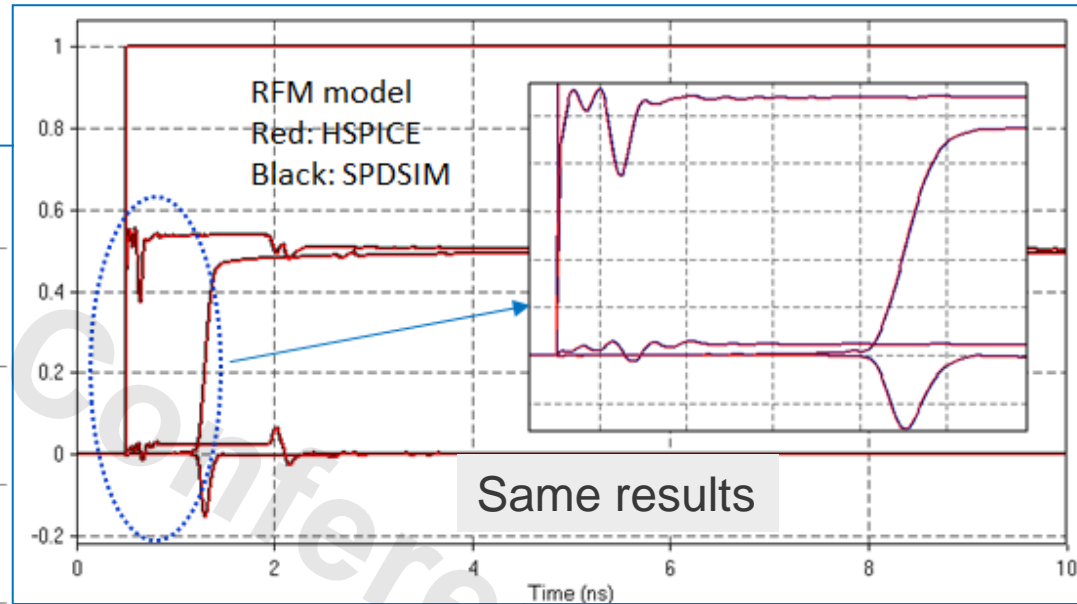
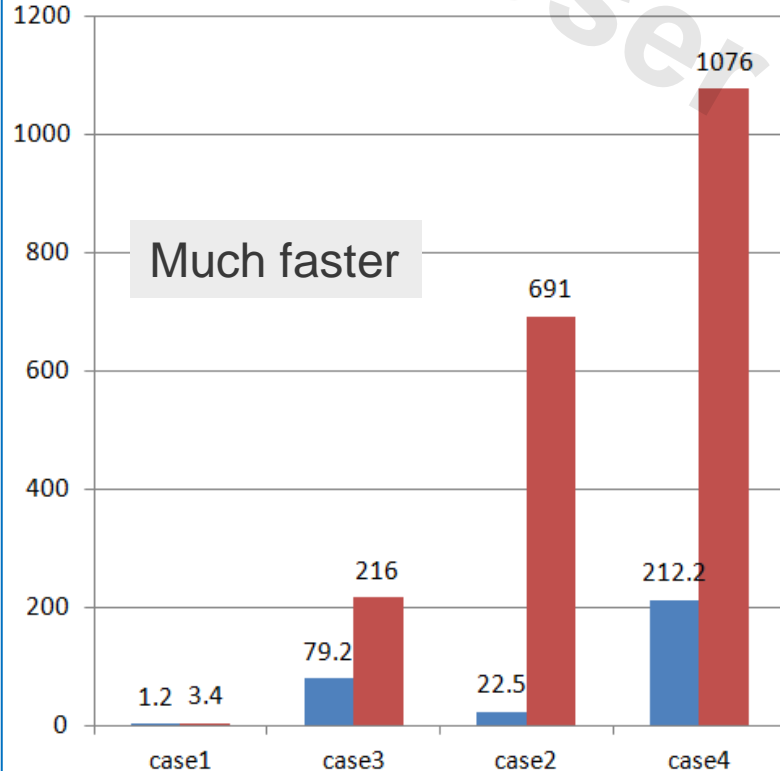


Impact of pre-driver current

Leading-edge analysis technology integrated with Allegro

S-parameter → SPICE macro model

CPU time for TD simulation (s)



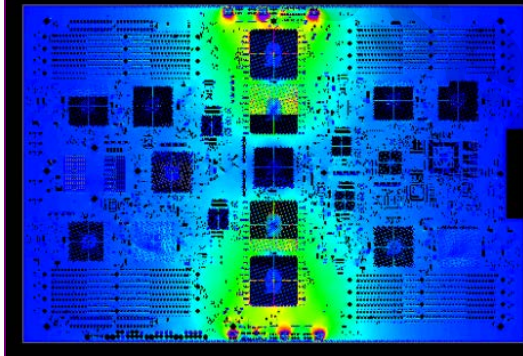
TD simulation using BBS
circuit model runs faster

Leading-edge analysis technology integrated with Allegro

Multi-physics simulations

PowerDC

DC Current Analysis Current Density



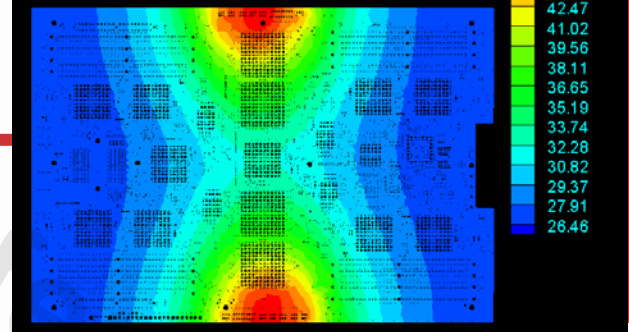
Both electrical resistance and leakage power dissipation increase at higher temperatures

Current density is an input for heat transfer analysis



Temperature is an input for DC current analysis

Heat Transfer Analysis Temperature

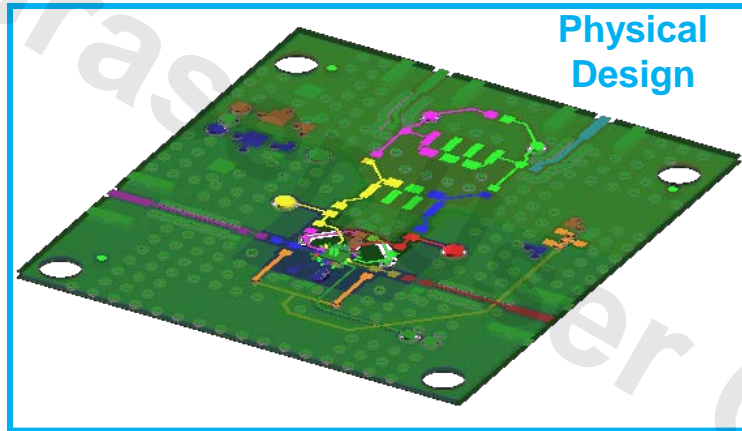


Joule and component heating will change temperature distribution

- The first integrated and automated electrical/thermal co-simulation tool to help designers meet the new design challenge

Leading-edge analysis technology integrated with Allegro

Thermal-RC extraction

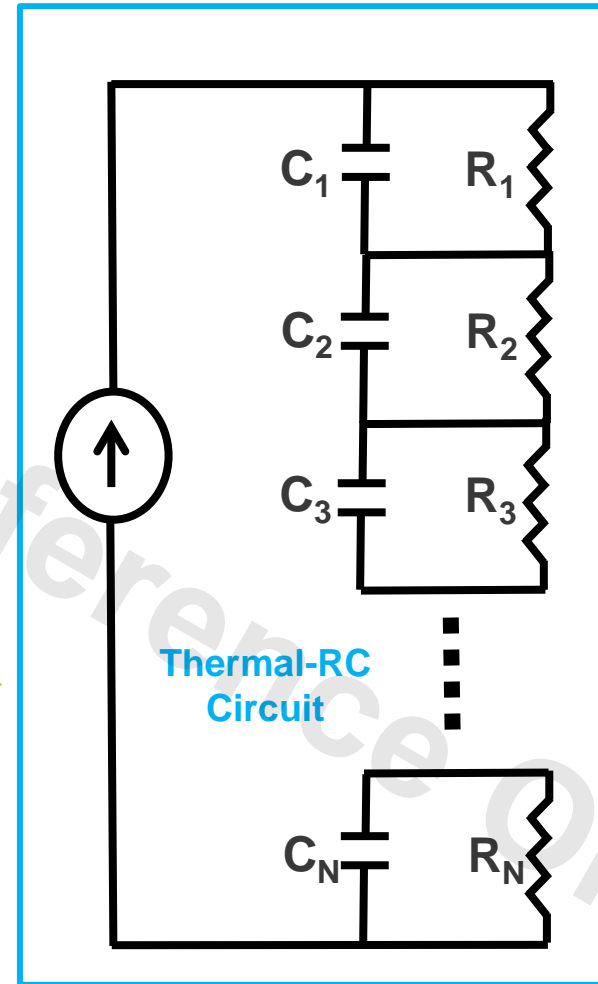


Finite Element Model

$$\nabla^T k \nabla T + Q = \rho c \frac{\partial T}{\partial t}$$
$$[K]\{T\} + [M]\frac{d\{T\}}{dt} = \{B\}$$

- One-time thermal-RC extraction
- Multiple transient analyses with a circuit simulator

Patent
Pending



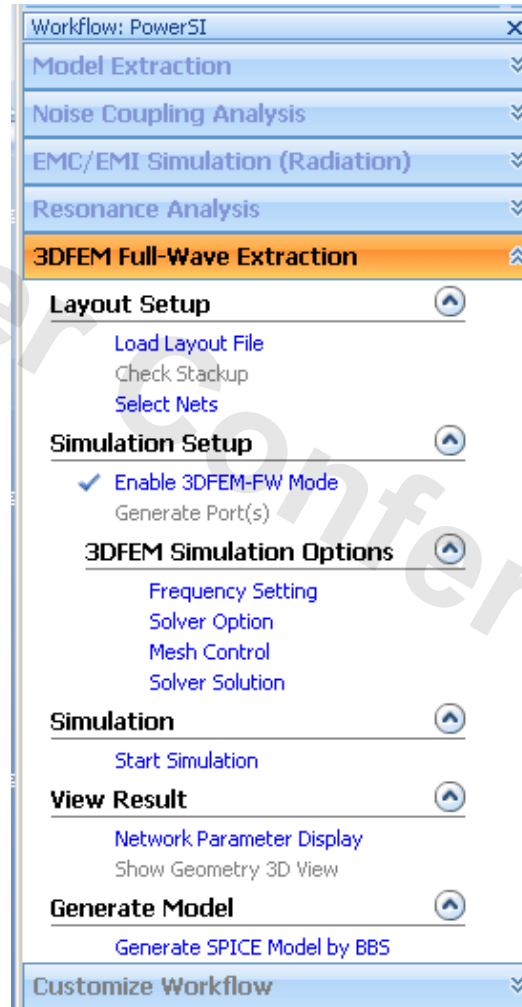
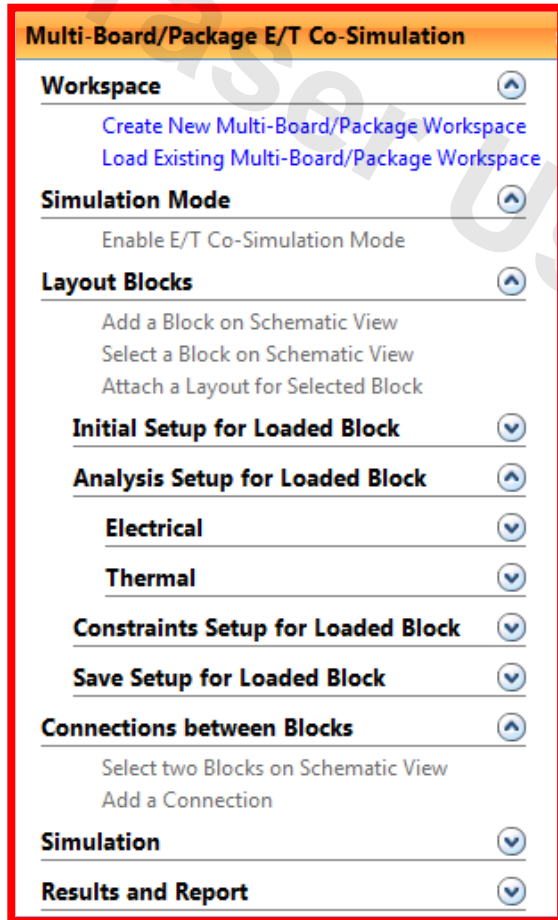
Agenda

- Leading-edge analysis technology integrated with Allegro
- Industry-renowned workflow
- Complete SI/PI/EMI solutions

- ✓ Industry-leading workflows
- ✓ Direct interface with Allegro®/APD/SiP
- ✓ Many useful model setup wizards
- ✓ Many SI/PI utilities
- ✓ Automated signoff report generation
- ✓ ...

Meticulous implementation

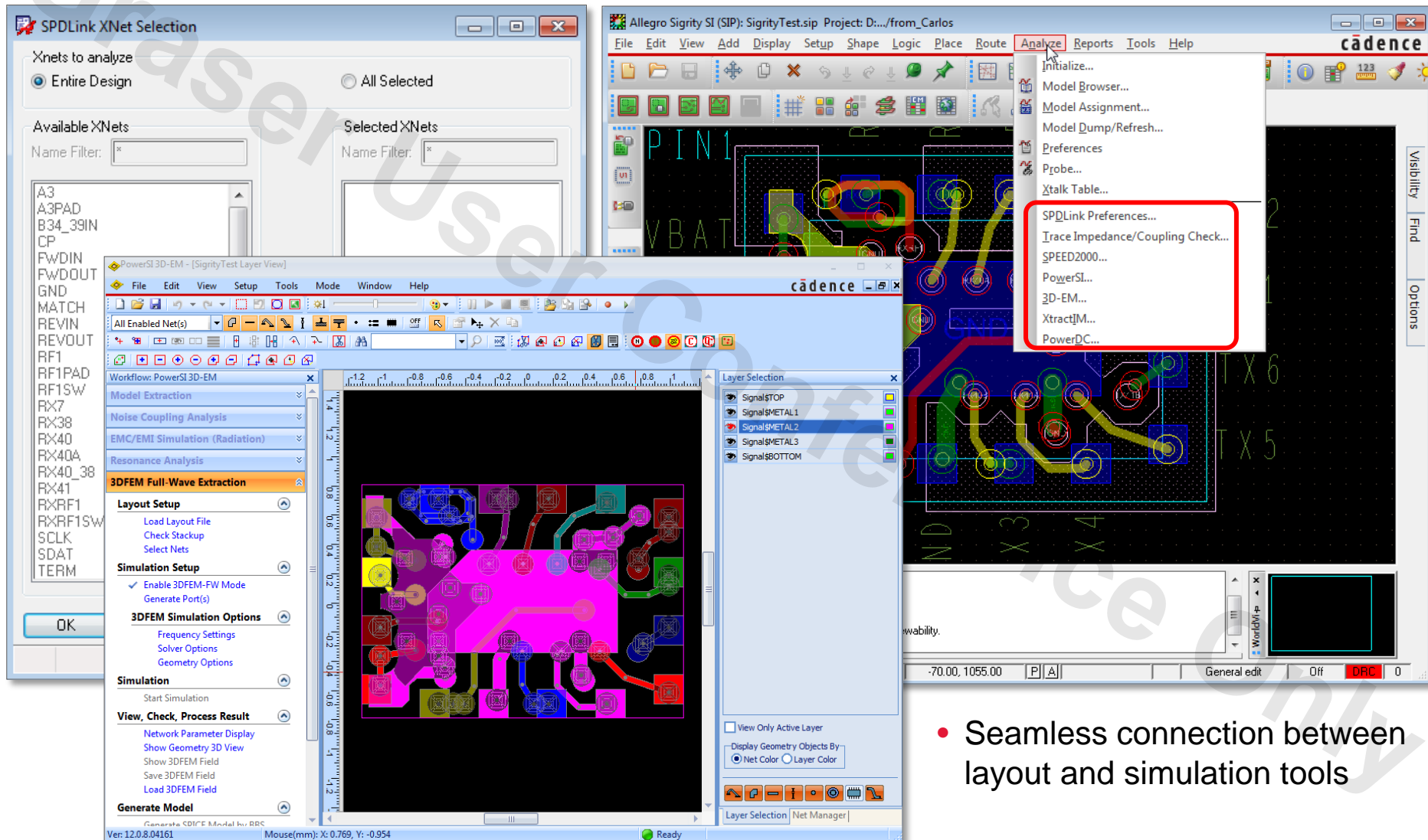
Industry-leading workflows



- Various application-specific workflows for easy learning and usage

Meticulous implementation

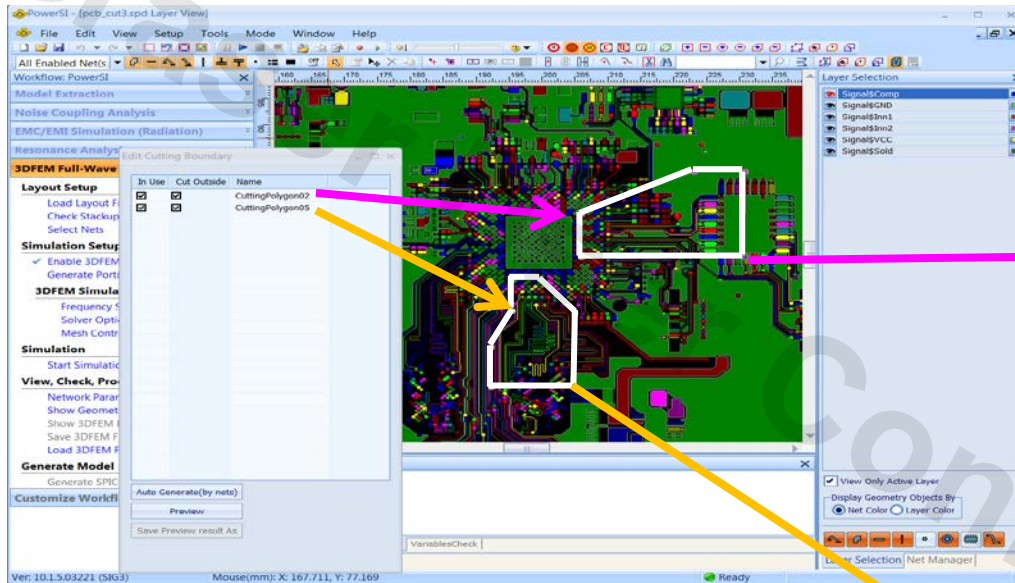
Direct interface with Allegro/APD/SiP



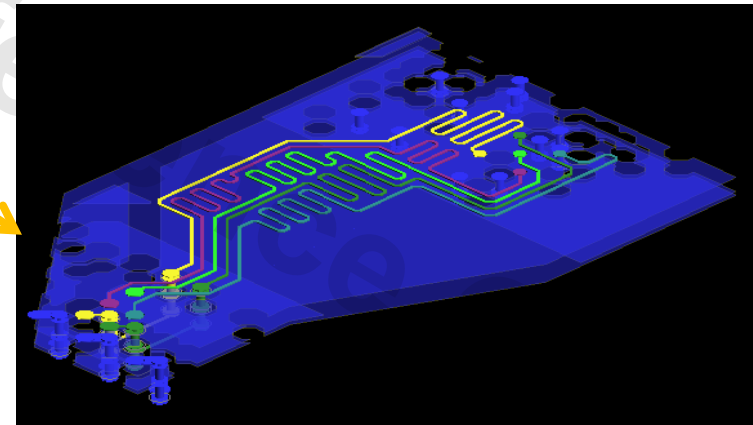
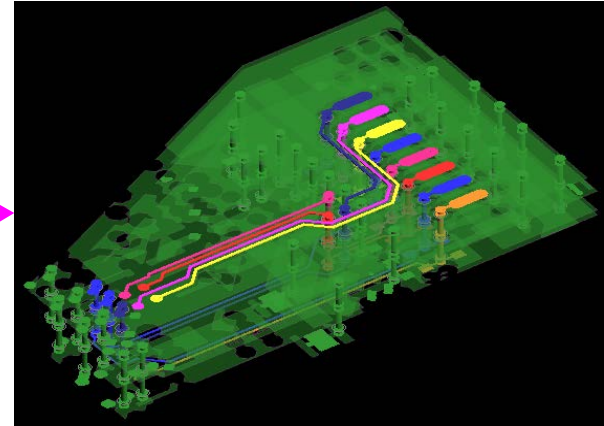
- Seamless connection between layout and simulation tools

Meticulous implementation

Many useful model setup wizards



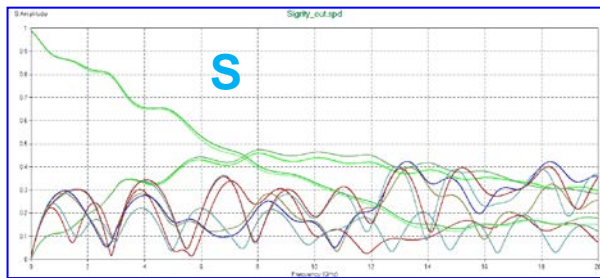
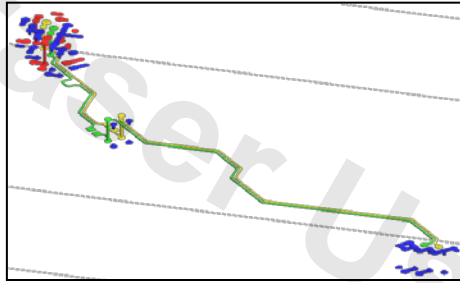
Geometry Cutting Wizard



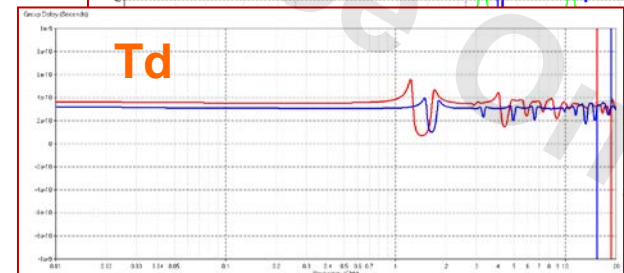
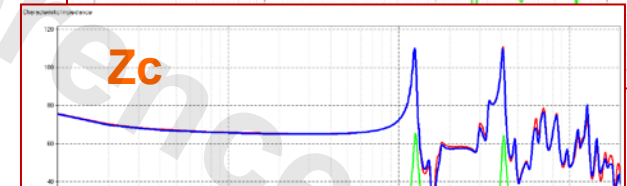
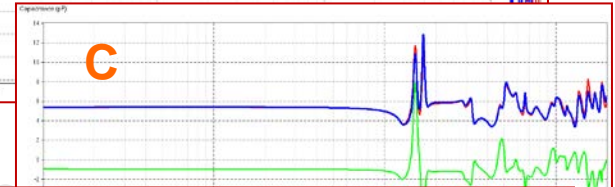
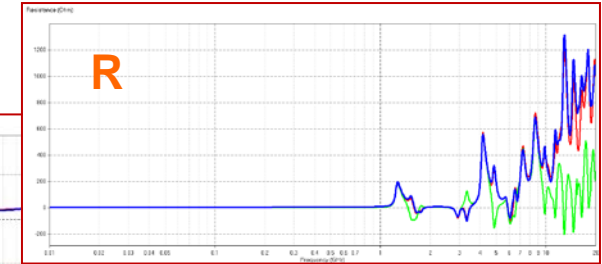
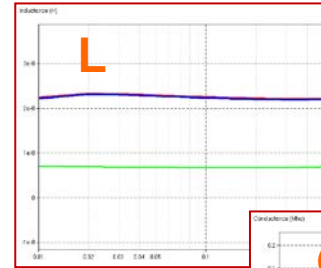
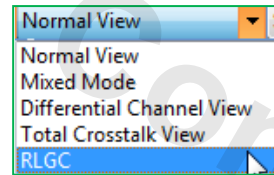
- Port wizard for automated port setup
- Wizard for PCB fiber weaving and RFIC deep-trenched isolation patterns
- Sweeping manager for parametric sweep
- Automated model cutting by polygon
- Cut-stitch wizard for long signal lines
- VRM setup wizard
- ...

Meticulous implementation

Many useful SI/PI utilities



- $S \rightarrow RLGC$
- $S \rightarrow TDR/TDT$
- Cascading
- De-embedding
- ...



Meticulous implementation

Signoff report generation

- Automated and configurable HTML report

PowerDC Simulation Report

Date: 13:34 November 25, 2013

- 1 General information**
 - 1.1 Spd file name and location
 - 1.2 Board Stackup
 - 1.3 Layout Top and Bottom Layer views
- 2 Simulation Setup**
 - 2.1 Electrical Setup
 - 2.2 Thermal Setup
 - 2.2.1 Ambient Setup
 - 2.2.2 Thermal Component Setup Table
 - 2.2.3 PCBComponent Setup Table
 - 2.2.4 PKG-Die Setup Table
 - 2.2.5 PKG-BGA Setup Table
- 3 Results**
 - 3.1 Electrical Result Table
 - 3.2 DC Analysis Block Diagram Result

| | Actual Voltage(V) | Current(A) | IR Drop Simulated | Specification | Pass/Fail |
|----|-------------------|------------|----------------------------|------------------------|-----------|
| U2 | 3.226 | 3 | $\Delta V = 74.4mV(2.3\%)$ | 3.3 V ⁺ 2 % | Fail_V |
| U1 | 3.218 | 5 | $\Delta V = 82.2mV(2.5\%)$ | 3.3 V ⁺ 2 % | Fail_V |

Note:

- IRdrop on net is calculated on Power net only.
- IRdrop Simulated in the right table is IRdrop of both Power and GND net (if both nets are enabled).
- If a net has current flow from different sources, IRdrop is
- Setup can be edited in the blue numbers. After editing, si

Abbreviation info:
Abbr_Vrm1=VRM_VRM_3p3_+3.3V_GND

Options

Change the 'Report' options in PowerDC

General Information

Report template (*.htm):

Notes:

Sign Off Report Option

| | | |
|--|---|---|
| <input checked="" type="checkbox"/> Spd File Name and Location | <input checked="" type="checkbox"/> Board Stackup | <input checked="" type="checkbox"/> Layout Top and Bottom Layer Views |
| <input checked="" type="checkbox"/> Simulation Setup | <input checked="" type="checkbox"/> Result Table | <input checked="" type="checkbox"/> DC Analysis Block Diagram Result |
| <input checked="" type="checkbox"/> Via Information | <input checked="" type="checkbox"/> Plane Information | <input type="checkbox"/> Resistance Measurement |

Max Number: Max Number:

Optional Plots

| | |
|---|--|
| <input type="checkbox"/> Power Loss Plot | <input type="checkbox"/> Temperature Plot |
| <input type="checkbox"/> Via Current Plot | <input type="checkbox"/> Heat Flux Plot |
| <input type="checkbox"/> Plane Current Density Plot | <input type="checkbox"/> Conductivity Plot |
| <input type="checkbox"/> Pin Voltage/IRdrop Plot | <input type="checkbox"/> Fusion Current Density Plot |
| <input type="checkbox"/> Plane Power Density Plot | <input type="checkbox"/> Mean Time To Failure Plot |
| <input type="checkbox"/> Pin Resistance Plot | |
| <input type="checkbox"/> Voltage Distribution Plot | |

☐ Display one plot for each power net and one plot for ground net

Layer Selection

| |
|--|
| <input checked="" type="checkbox"/> Signal\$TOP |
| <input checked="" type="checkbox"/> Signal\$L1 |
| <input checked="" type="checkbox"/> Signal\$L2 |
| <input checked="" type="checkbox"/> Signal\$BOTTOM |

Default Apply OK Cancel

Agenda

- Leading-edge analysis technology integrated with Allegro
- Industry-renowned workflow
- Complete SI/PI/EMI solutions

- ✓ Layout checks
- ✓ Model-based high-speed bus simulation
- ✓ Layout-based time-domain simulation
- ✓ Layout-based frequency-domain simulation
- ✓ Decap placement optimization
- ✓ High-speed bus simulation
- ✓ Multi-board-package simulation
- ✓ IOSSO
- ✓ Chip-pkg-board co-simulation
- ✓ EMI/EMC simulation
- ✓ Electrical/thermal co-simulation
- ✓ Package thermal parameters extraction
- ✓ RFIC passive component extraction
- ✓ Different levels for different needs
- ✓

Complete solutions

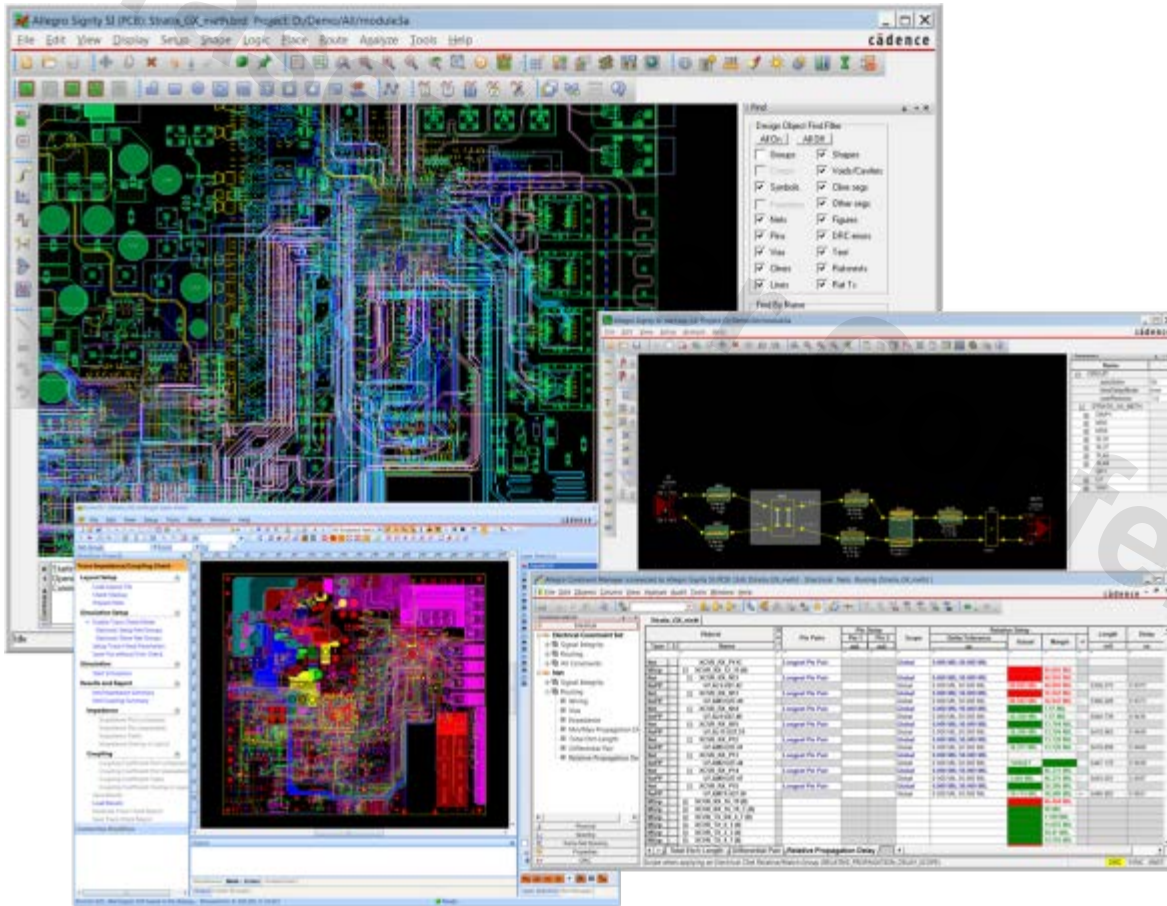
Cover broad SI/PI/EMI needs

- Layout PDN design DC/AC check
 - DC check
 - AC check
- Layout SI check
 - Geometry-based physical check
 - Simulation-based electrical check
- PDN simulation
 - DC simulation and signoff
 - Electrical/thermal co-simulation
 - AC frequency domain simulation and optimization
 - Chip/PKG/PCB co-simulation
- Power-aware SI simulations
 - High-speed serial link simulation
 - Parallel bus simulation
 - Chip/PKG/board IOSSO co-simulation
- EMI simulation
 - Conductive EMI
 - Radiative EMI
 - EMC compliance check
- SI/PI/TI modeling
 - RFIC passive component extraction
 - Package thermal parameters extraction
 - Electrical/thermal
 - IBIS



Allegro Sigrity SI and Allegro PCB Editor

Integrated high-speed design and analysis



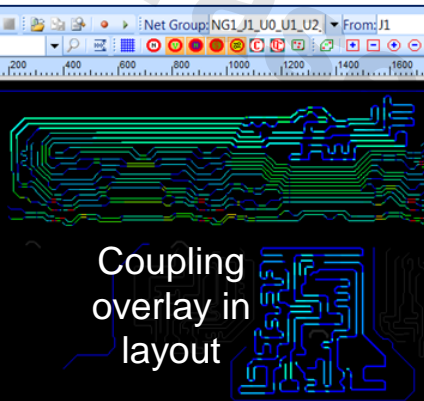
Allegro Sigrity SI

No manual translation is required to analyze selected signals from the physical board or extract them into the SigXplorer module. Analysis results are reported in the same constraint manager used by Allegro PCB Editor. Coupled differential pairs and nets extended through discrete components (x-nets) are automatically identified, analyzed, and/or extracted.

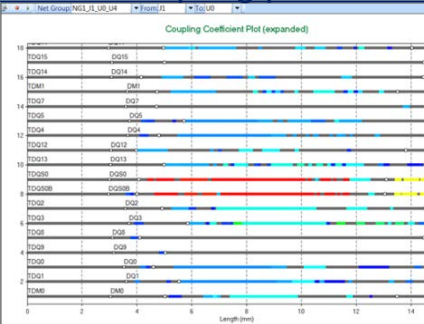
Complete solutions

Geometry-based and simulation-based layout checks

DRC.....ERC



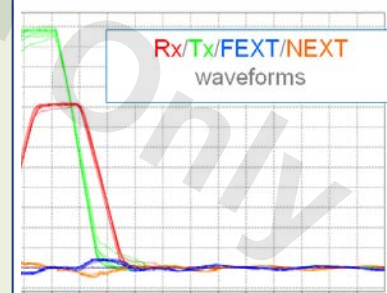
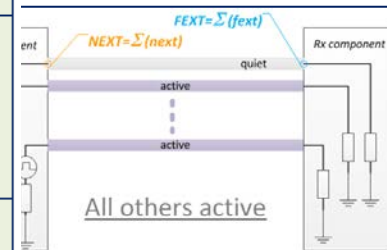
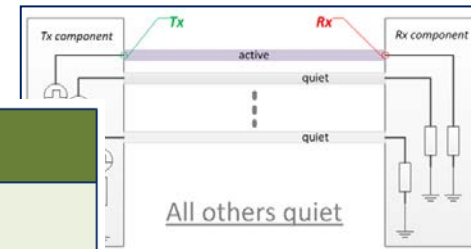
Coupling plot



Coupling table

| Net | Length(mm) | Trace Name | Length(mm) | % of its net length | Coupled Lines | Coupling Coefficient |
|-----|------------|------------------------|------------|---------------------|---------------|----------------------|
| A1 | 136.476 | Trace3002_A6 | 2.943 | 1.9% | | |
| A2 | 136.876 | Trace3002_A6 | 0.444 | 0.3% | | |
| A3 | 137.888 | Trace3002_A6 | 0.433 | 0.3% | | |
| A4 | 138.940 | Trace3002_A6 | 0.261 | 0.2% | | |
| A5 | 143.174 | Trace3002_A6 | 0.472 | 0.3% | | |
| A6 | 137.164 | Trace3002_Auto_2344-A6 | 1.288 | 0.9% | | 0.034 |
| A7 | 135.712 | Trace3002_Auto_2343-A6 | 0.833 | 0.6% | | 0.034 |
| A8 | 137.251 | Trace3002_Auto_2327-A6 | 0.218 | 0.1% | | 0.034 |
| A9 | 138.872 | Trace3002_Auto_2328-A6 | 0.793 | 0.5% | | 0.034 |
| A10 | 135.803 | Trace3002_Auto_2336-A6 | 0.698 | 0.5% | | 0.034 |
| A11 | 141.138 | Trace3002_Auto_2337-A6 | 0.803 | 0.5% | | 0.034 |
| A12 | 139.030 | Trace3002_Auto_2319-A6 | 0.207 | 0.1% | | 0.034 |
| A13 | 137.053 | Trace3002_Auto_2320-A6 | 0.261 | 0.1% | | 0.034 |
| A14 | 137.986 | Trace3002_Auto_2323-A6 | 0.419 | 0.3% | | 0.034 |
| A15 | 138.346 | Trace3002_Auto_2325-A6 | 1.254 | 0.9% | | 0.034 |
| A16 | 137.164 | Trace3002_Auto_2326-A6 | 0.297 | 0.2% | | 0.034 |
| A17 | 137.164 | Trace3002_Auto_2327-A6 | 1.119 | 0.8% | | 0.034 |

| Trace Impedance/Coupling Check | SI Metrics Check |
|--|--|
| Geometry-based | Simulation-based |
| Micro, individual, segment-level view (coupling %, Ω & mm) | Macro, combined net-level , view (mv & ps) |
| <u>Options</u> Check all nets Check selected nets Check nets in net groups | <u>Options</u> Level-1 simulation Level-2 simulation Level-3 simulation |
| <u>Results</u> Coupling coefficient Impedance Trace reference Summary & detailed tables Expanded & collapsed plots Layout overlay Layout cross probing HTML report | <u>Results</u> Waveforms: Tx / Rx / NEXT / FEXT v_min & v_max SI performance metrics HTML report |



Complete solutions

Layout-based time-domain SI/PI simulation

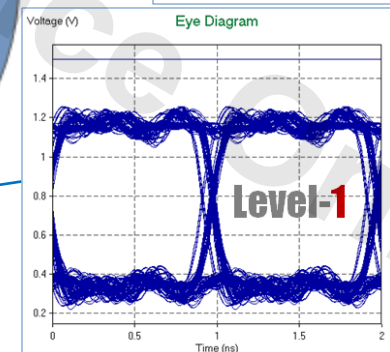
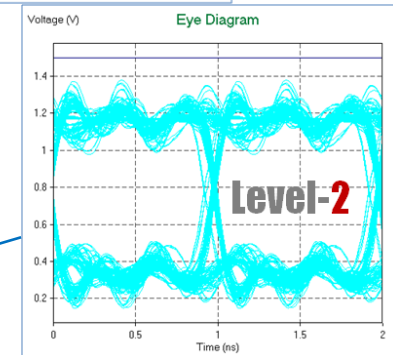
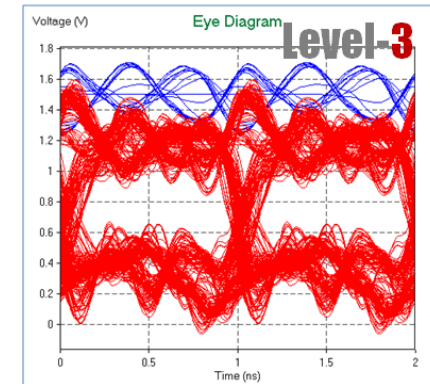
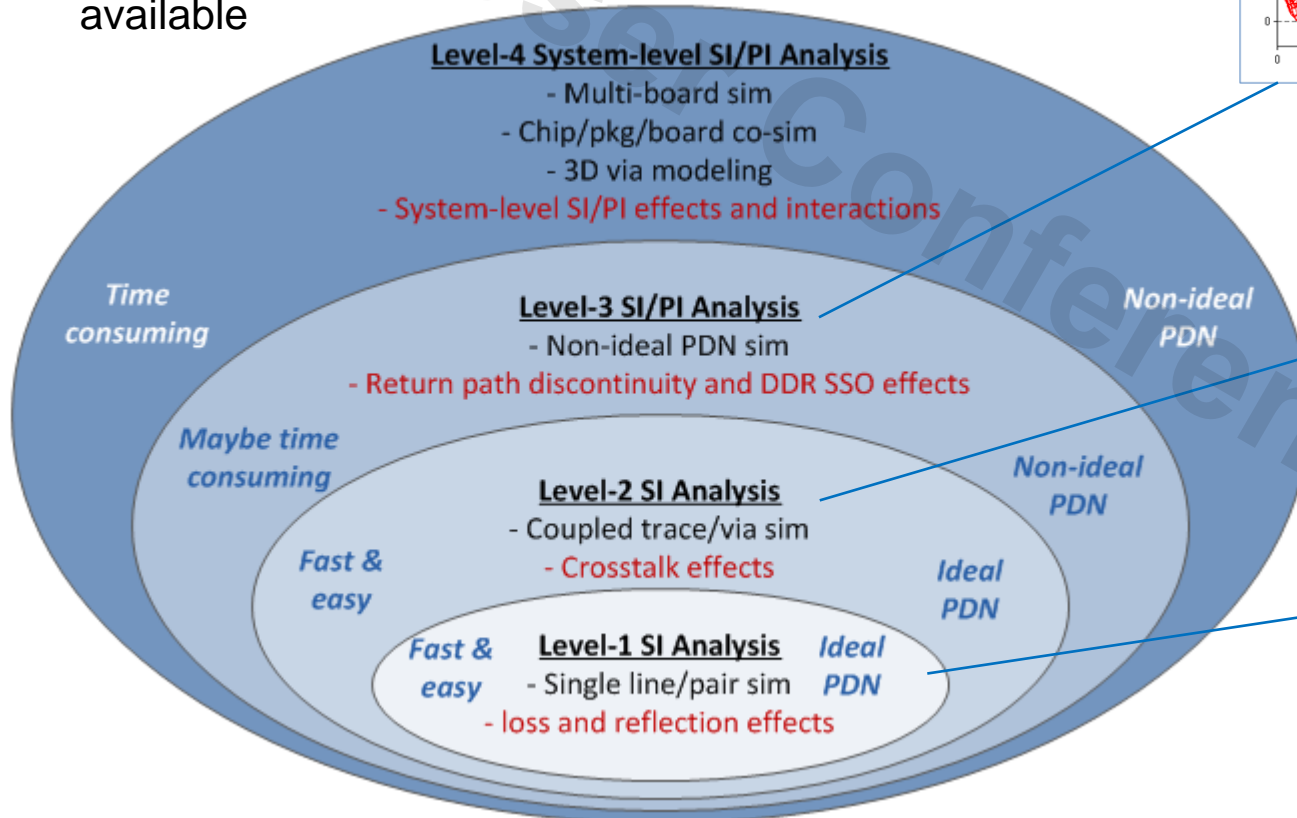
- SPEED2000™ is industry's only layout-based time-domain SI/PI tool
- Five major workflows available for SI/PI analysis at level-1 to level-3

| <u>Workflow 1</u> General SI Simulation | <u>Workflow 2</u> Trace Impedance/ Coupling Check | <u>Workflow 3</u> SI Performance Metrics Check | <u>Workflow 4</u> DDR Simulation | <u>Workflow 5</u> Time-domain PDN Simulation |
|--|--|---|---|---|
| Mainstream SI <i>L1/L2 for fast sim</i> Easy to setup; Sim runs fast Waveforms & measurements | Geometry based Trace impedance, coupling & reference check for entire board or net groups Results tables; Results plots; Layout overlay; Layout x-probing | Simulation based <i>L1/L2 for fast sim</i> <i>L3 for non-ideal PDN</i> Loss, reflection, xtalk check, typically by net groups Waveforms; Xtalk v_max & v_min | Layout-based DDR simulation <i>L1/L2 for fast sim</i> <i>L3 for SSO</i> No s-parameter model needed for on-board DRAMs Waveforms & measurements | Layout-based TD PDN sim PDN chip-pkg- board co-sim with -Voltus die mode -XcitePI IO model with die grid Voltage / current distributions; dynamic noise propagation |

Complete solutions

Different levels for different SI/PI/EMI needs

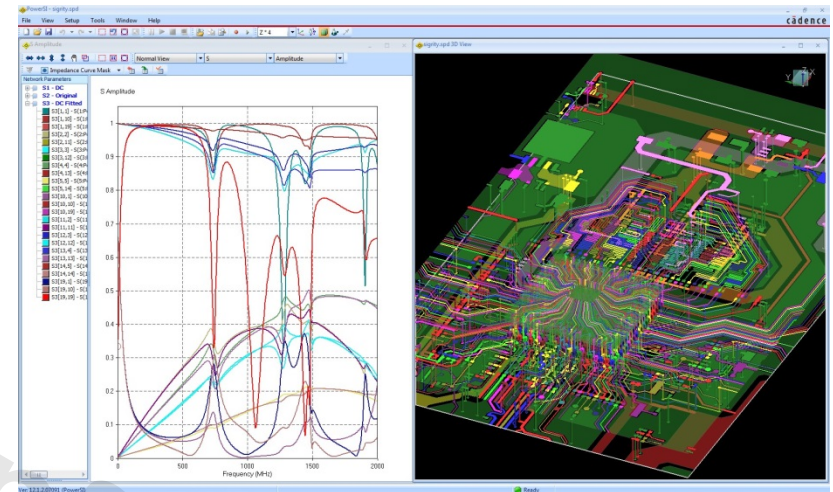
- Using Sigrity technology, SI/PI simulations can be done at 4 levels based on considerations of trace/via couplings and non-ideal PDN
- Both layout-based and model-based solutions are available



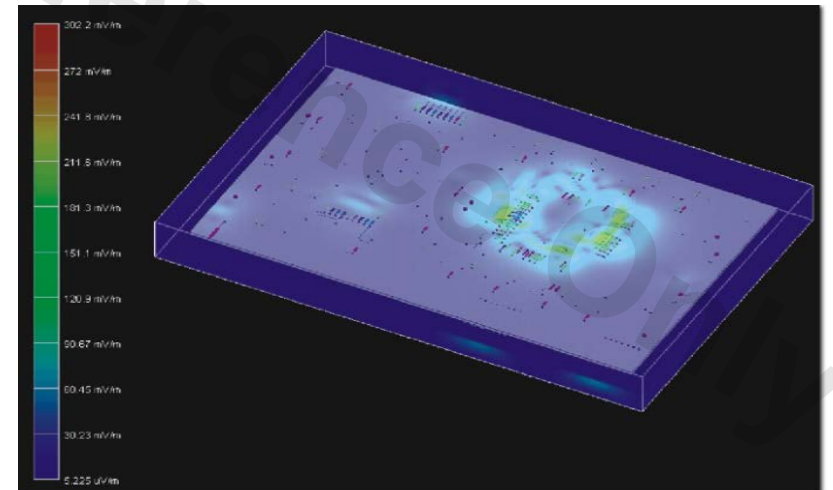
Complete solutions

Layout-based frequency-domain SI/PI simulation

- Market leader and product of choice where power and signal integrity analysis is essential
- Highly accurate modeling of IC package and PCB structures
- Single-ended and mixed-mode results and post-processing
- Adaptive frequency sampling and intelligent result storage
- Supports component / circuit models with unlimited terminals
- Unique capability for ensuring accuracy down to DC with integrated PowerDC analysis
- Targeted workflows to streamline setup operations
- Integration with full wave 3D EM solver

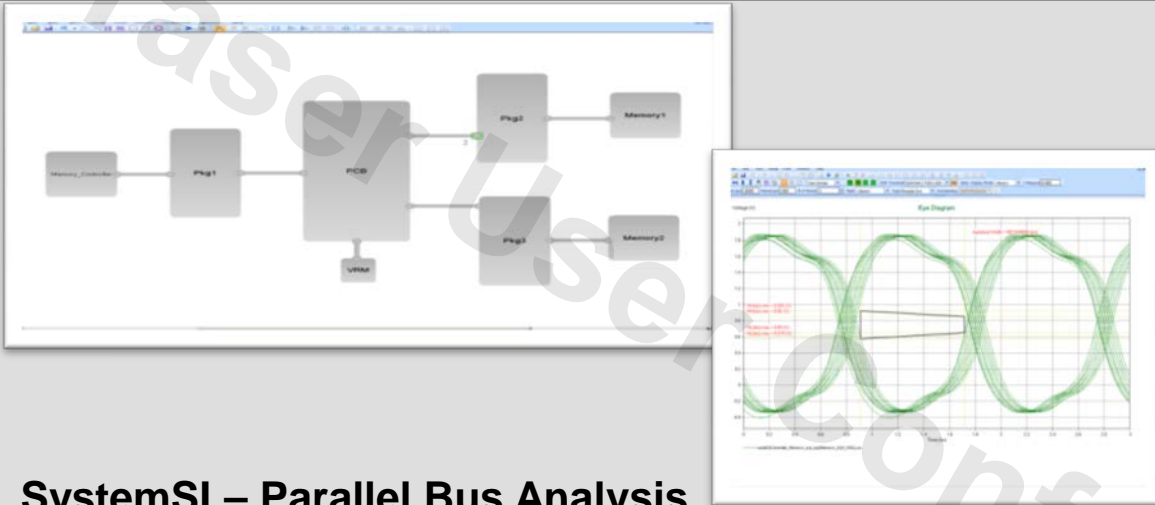


Frequency domain SI, PI and EMC

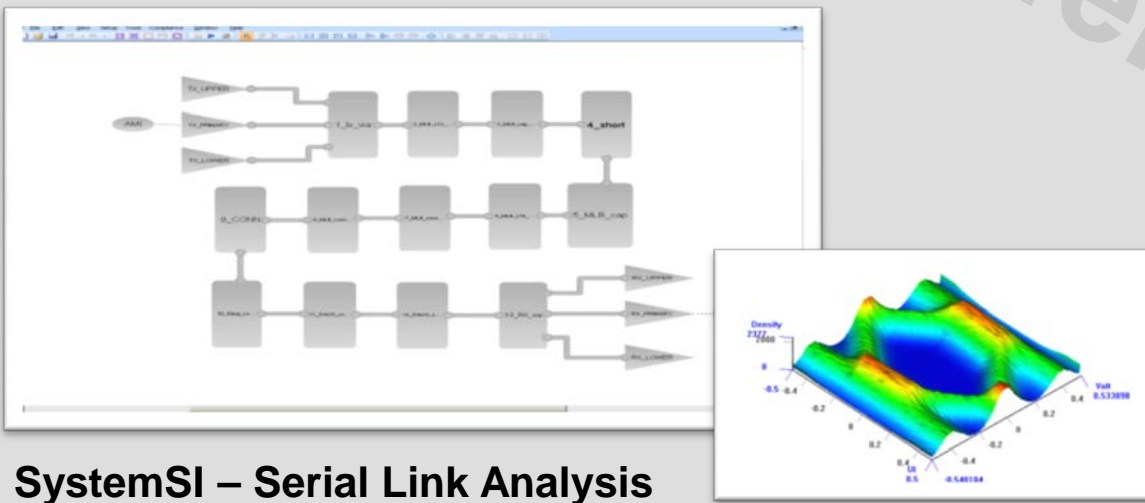


Complete solutions

High-speed bus simulation



SystemSI – Parallel Bus Analysis

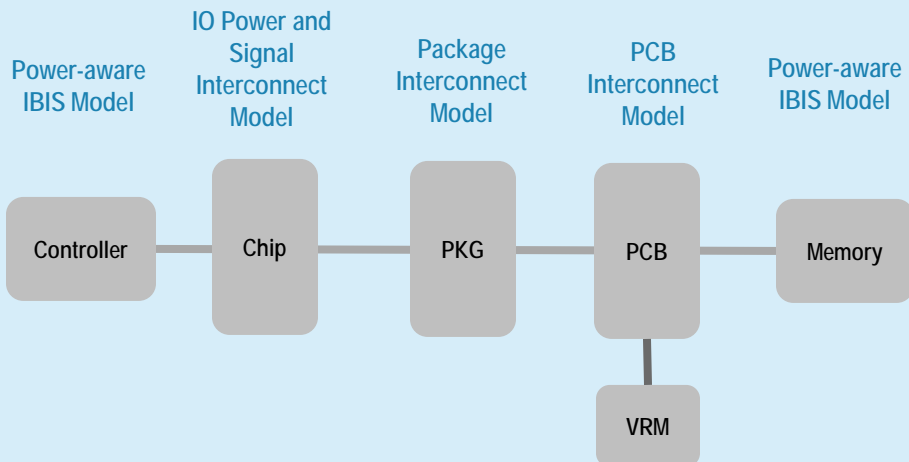
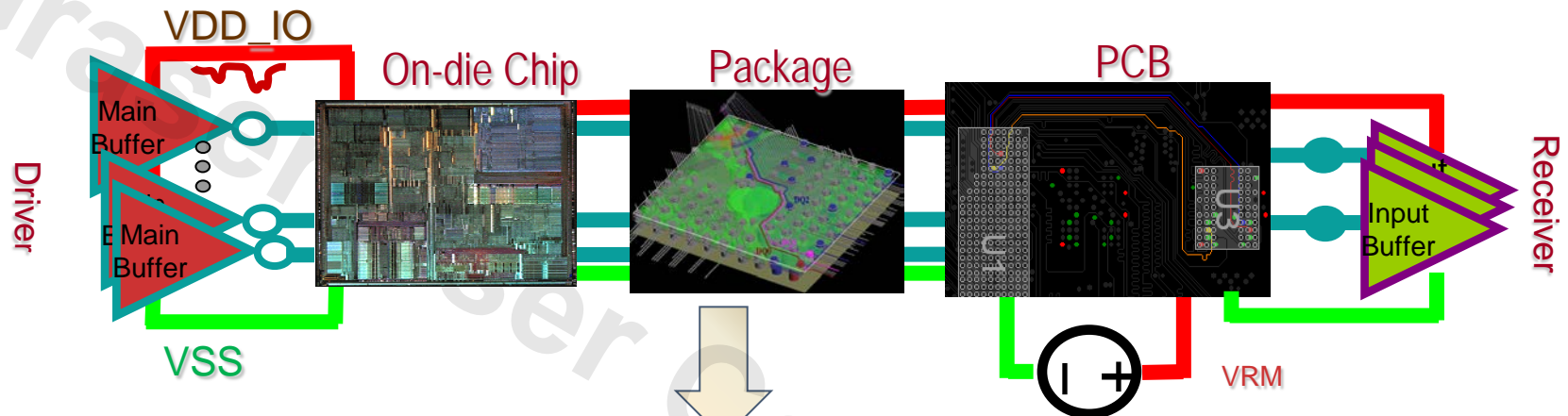


SystemSI – Serial Link Analysis

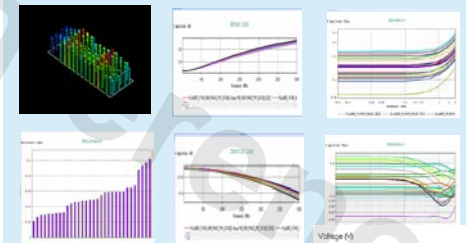
- Simplified model connections with Model Connection Protocol (MCP) and block-wise editor
- IBIS and SPICE-based power-aware system-level modeling
- Concurrent, comprehensive simulation of both SI and PI effects
- Highly automated JEDEC-based measurement, reporting, and crossprobing capabilities for DDR interfaces
- Advanced channel simulation engine for high-capacity serial link simulation and BER analysis
- Comprehensive, parameterized AML model library for modeling of advanced SerDes equalization

Complete solutions

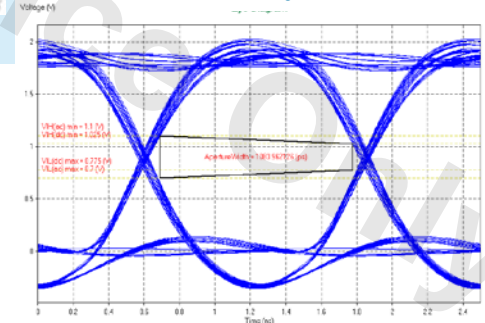
IOSSO



Chip/Package/Board Assessment Result

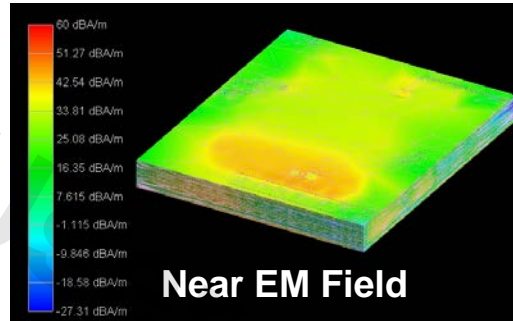
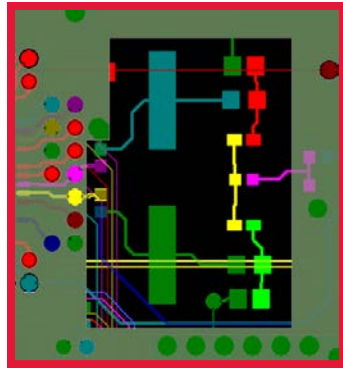


Co-Analysis Result

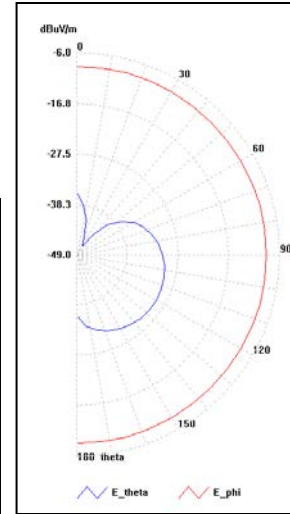
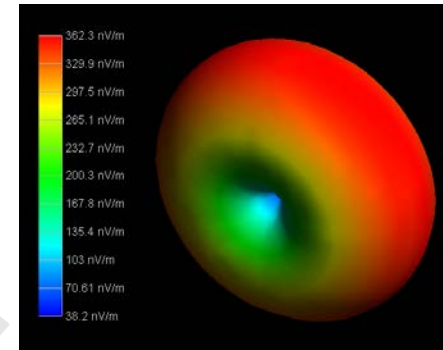


Complete solutions

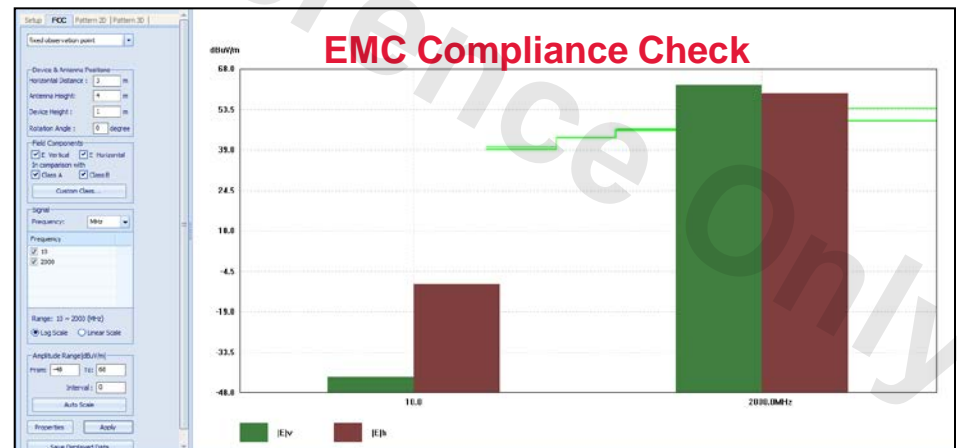
EMI/EMC



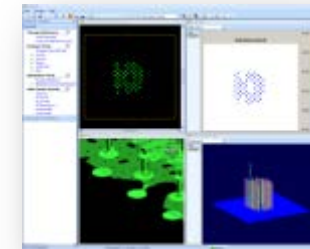
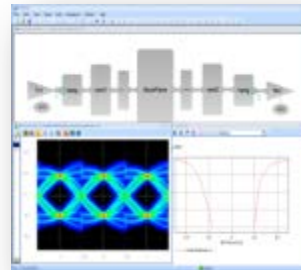
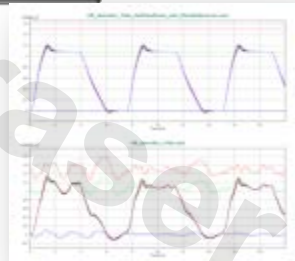
→ **Far EM Field**



EMC Compliance Check



Allegro Sigrity SI Options



Power Aware SI Option

- SIGR011 Broadband SPICE®
- SIGR021 T2B™
- SIGR031 CAD Translators
- SIGR301 PowerSI™
- SIGR311 3D-EM
- SIGR401 SPEED2000™
- SIGR556 SystemSI™ – PBA II

Serial Link SI Option

- SIGR011 Broadband SPICE
- SIGR021 T2B
- SIGR031 CAD Translators
- SIGR301 PowerSI
- SIGR311 3D-EM
- SIGR506 SystemSI – SLA II

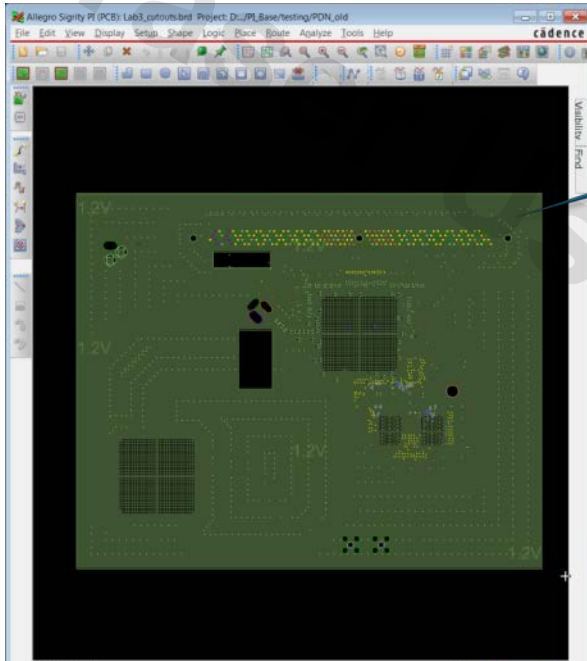
Package Assessment and Model Extraction Option

- SIGR031 CAD Translators
- SIGR201 PowerDC™
- SIGR311 3D-EM
- SIGR801 XtractIM™

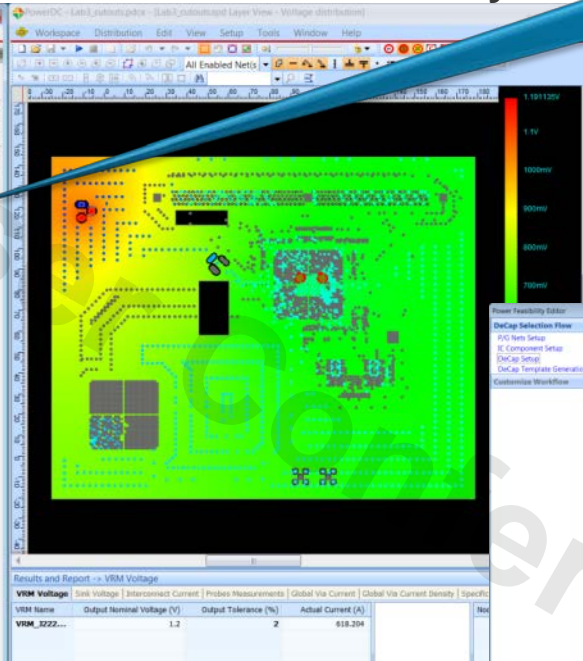
Note: Each option is a single user license. Only one of the products listed in each option can be run at a time.

Allegro Sigrity PI and Allegro PCB Editor Integrated design and power analysis

Floorplanner



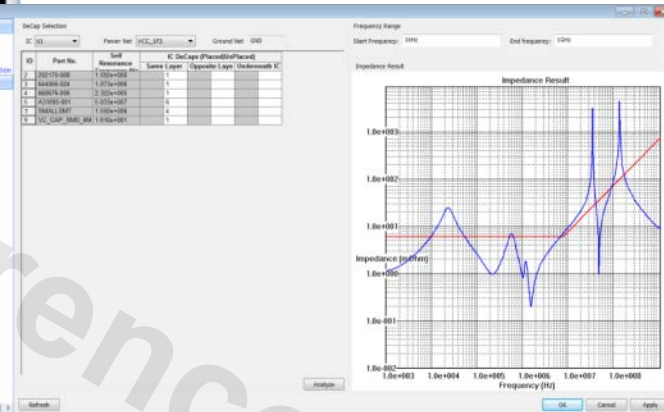
DC Analysis



- Allegro based editor for .brd, .mcm, or .sip
- Layout editing and routing

• Sigrity technology with cross-probing to layout

Power Feasibility Editor



- New unique constraint driven DeCap flow

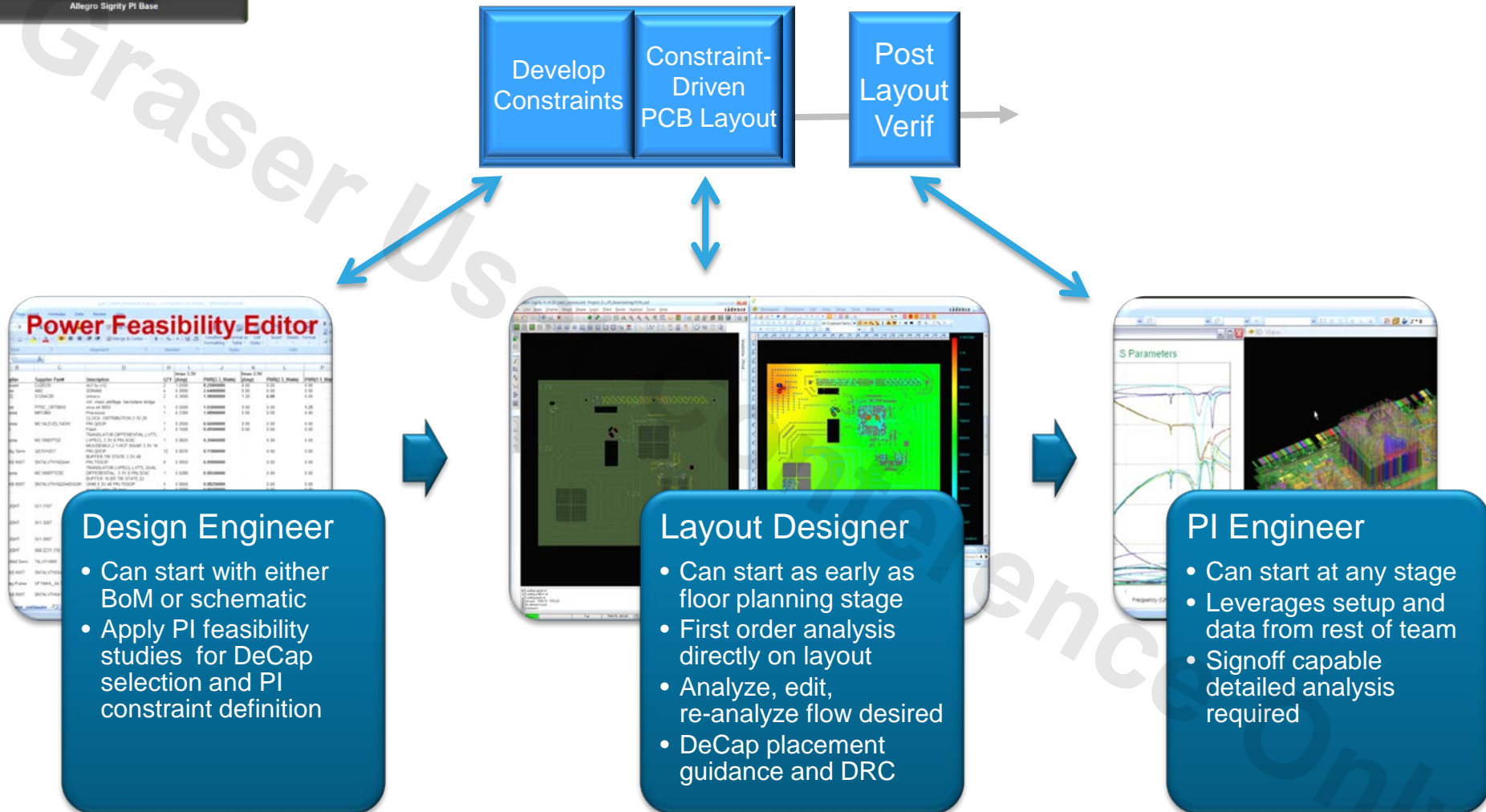
Constraint Manager

| Type | Name | Setback Distance | Number of Capacitors | Package |
|------|-------------------------------|------------------|----------------------|----------------------|
| | | Same Layer | Opposite Layer | Underneath Component |
| Pin | SGX_descon13_v2 | | | |
| Pin | MY_PI_CSET | 100.000 | 100.000 | |
| Pin | CAP_SMD_NPOL_0_0603_0.1UF | | 5 | 5 |
| Pin | CAP_SMD_NPOL_0_0603_0.01UF | | 6 | 6 |
| Pin | CAP_SMD_NPOL_0_0603_120PF | | 6 | 6 |
| Pin | CAP_SMD_NPOL_0_0603_120PF | 150.000 | 150.000 | |
| Pin | CAP_SMD_NPOL_0_0603_0.1UF | | 5 | 5 |
| Pin | CAP_SMD_NPOL_0_0603_22.0UF | | 10 | 10 |
| Pin | CAP_SMD_NPOL_0_0603_120PF | | 4 | 3 |
| Pin | CAP_SMD_NPOL_1_CAP_0603_100PF | | | 10 |



Allegro Sigrity PI and Allegro PCB Editor

Constraint Driven Power Integrity

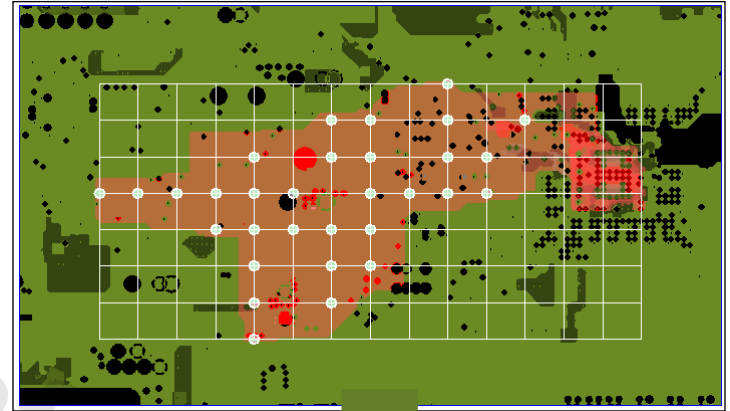


Complete solutions

Decoupling capacitor optimization

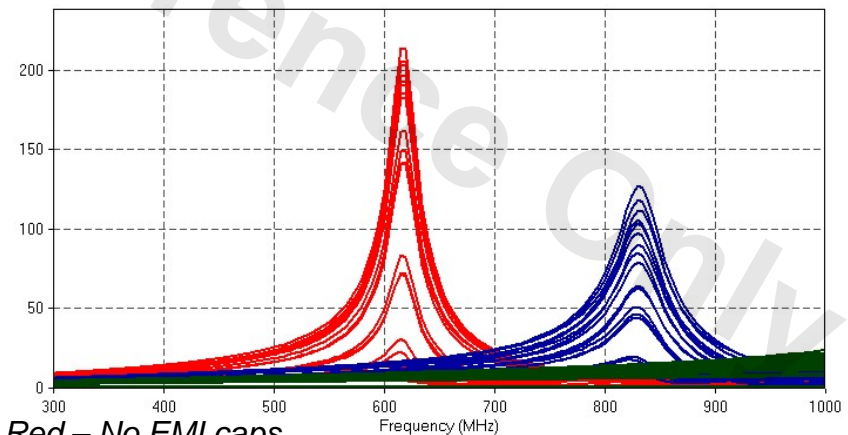
- Automated DeCap optimization of placement and value selection
- Multiple objectives: performance, cost, area, number
- Device impedance and EMI resonance checking
- DeCap loop inductance analysis to identify poorly mounted caps
- Device per-pin inductance checking and display

Automated positioning and selection of EMI decoupling capacitors



Impedance (Ohm)

Impedance vs. Frequency



Red – No EMI caps

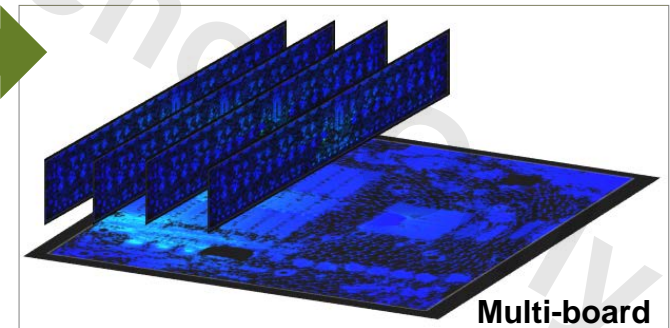
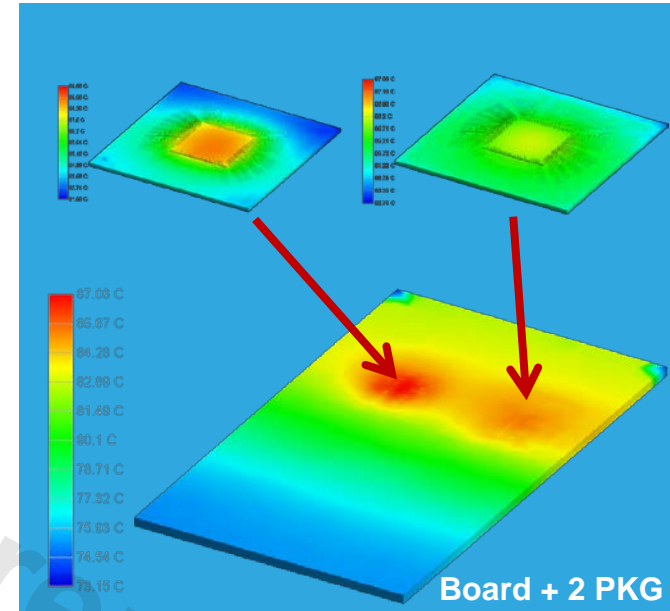
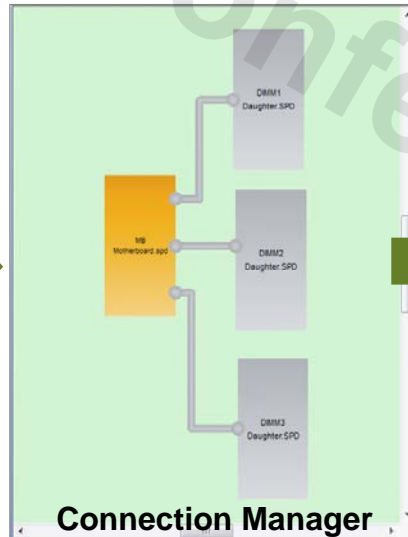
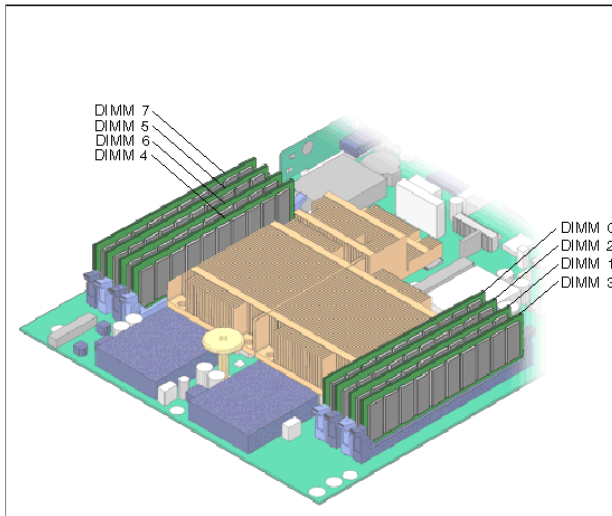
Blue – 1 cap; Green – 3 caps

cadence

Complete solutions

Multi-board-package SI/PI simulations

- Industry's first layout-based multi-board-package simulation flow



Complete solutions

Extraction of package thermal parameters

Thermal Analysis Results -> Theta-JA

Theta-JA | Theta-JMA | Theta-JB | Theta-JC | 2-Resistor CTM | DELPHI CTM | MCP-JA | MCP-JMA | MCP-JB

☒ Present ☐ Loaded

Still Air Junction-to-Ambient Thermal Parameters

| Theta-JA [C/W] | Psi-JT [C/W] | Psi-JB [C/W] |
|----------------|------------------|--------------|
| 14.9486 | 0.0277034 | 8.12 |

Thermal Analysis Results -> Theta-JB

Theta-JA | Theta-JMA | **Theta-JB** | Theta-JC

☒ Present ☐ Loaded

Junction-To-Board Thermal Resistance

| Theta-JB [C/W] |
|----------------|
| 8.22546 |

Thermal Analysis Results -> Theta-JC

Theta-JA | Theta-JMA | Theta-JB | **Theta-JC**

☒ Present ☐ Loaded

Junction-To-Case Thermal Resistance

| Theta-JCtop [C/W] |
|-------------------|
| 0.0886686 |

Thermal Analysis Results -> 2-Resistor CTM

Theta-JA | Theta-JMA | Theta-JB | Theta-JC | **2-Resistor CTM** | DELPHI CTM | MCP-JA | MCP-JMA | MCP-JB

☒ Present ☐ Loaded

2-Resistor CTM

| Theta-JCtop [C/W] | Theta-JB [C/W] |
|-------------------|----------------|
| 0.0886686 | 8.22546 |

Thermal Analysis Results -> Theta-JMA

Theta-JA | **Theta-JMA** | Theta-JB | Theta-JC | 2-Resistor CTM | DELPHI CTM | MCP-JA | MCP-JMA | MCP-JB

☒ Present ☐ Loaded

Forced Convection Junction-to-Ambient Thermal

| Air Speed (m/s) | Theta-JMA [C/W] | Psi-JMT [C/W] | Psi-JMB [C/W] |
|-----------------|-----------------|---------------|----------------|
| 0 | 14.9486 | 0.0277034 | 8.12 |
| 1 | 12.9457 | 0.0278125 | 8.07926 |
| 2 | 12.2224 | 0.028079 | 7.98021 |
| 3 | 11.7431 | 0.0283717 | 7.87262 |

Thermal Analysis Results -> DELPHI CTM

Theta-JA | Theta-JMA | Theta-JB | Theta-JC | 2-Resistor CTM | **DELPHI CTM** | MCP-JA | MCP-JMA | MCP-JB

☒ Present ☐ Loaded

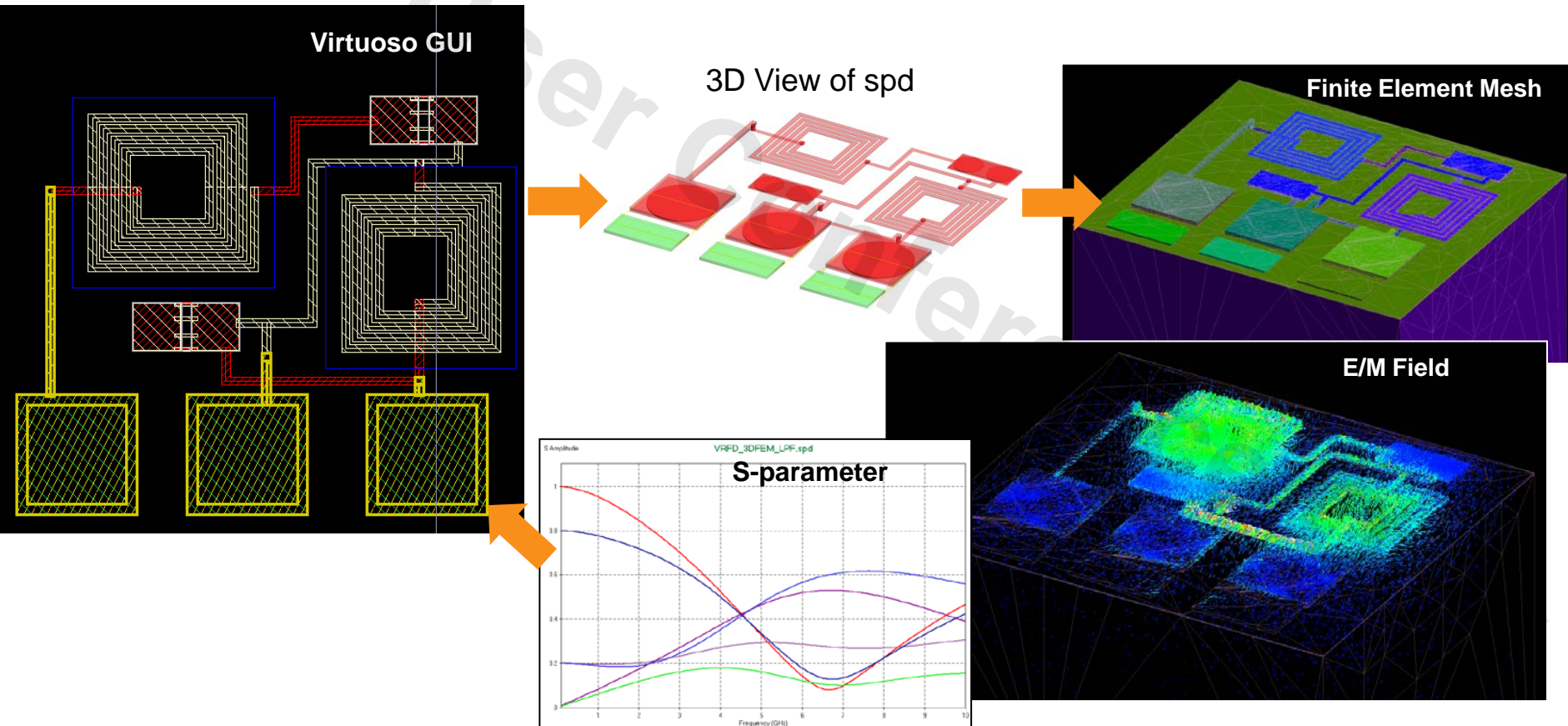
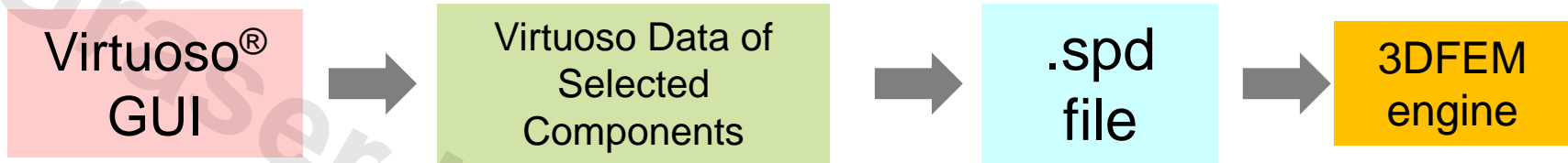
DELPHI Compact Thermal Model

Optimum values of thermal links [C/W]

| | Junction | Top Inner | Top Outer | Side | Bottom Outer | Bottom Inner |
|--------------|-----------------|-----------|-----------------|----------|-----------------|--------------|
| Junction | N/A | 0.100001 | N/A | N/A | N/A | 8.59441 |
| Top Inner | 0.100001 | N/A | N/A | N/A | N/A | N/A |
| Top Outer | N/A | N/A | N/A | 0.100576 | 0.101073 | 7.80477 |
| Side | N/A | N/A | 0.100576 | N/A | 0.100854 | N/A |
| Bottom Outer | N/A | N/A | 0.101073 | 0.100854 | N/A | N/A |
| Bottom Inner | 8.59441 | N/A | 7.80477 | N/A | N/A | N/A |

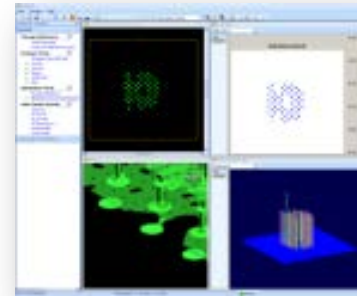
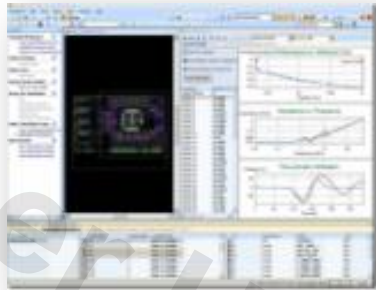
Complete solutions

RFIC passive component extraction





Allegro Sigrity PI Options



Power Integrity Signoff and Optimization Option

- SIGR031 CAD Translators
- SIGR051 OptimizePI
- SIGR201 PowerDC
- SIGR301 PowerSI
- SIGR311 3D-EM

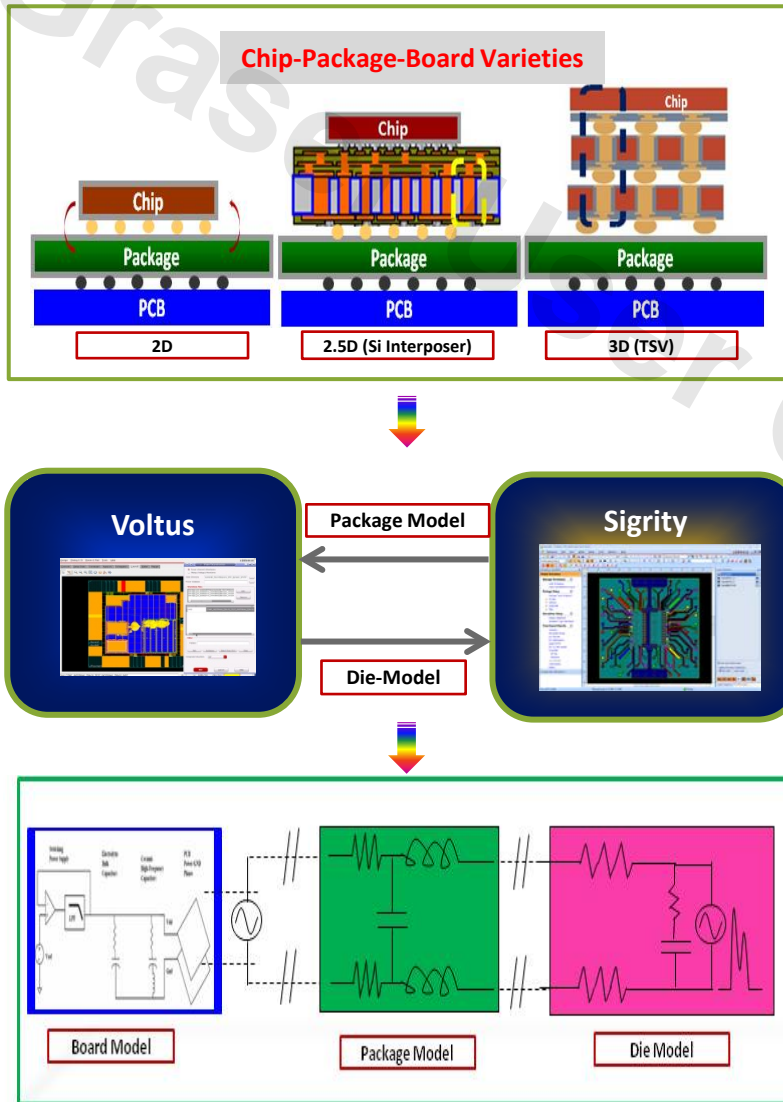
Package Assessment and Model Extraction Option

- SIGR031 CAD Translators
- SIGR201 PowerDC
- SIGR311 3D-EM
- SIGR801 XtractIM

Note: Each option is a single user license. Only one of the products listed in each option can be run at a time.

Complete solutions

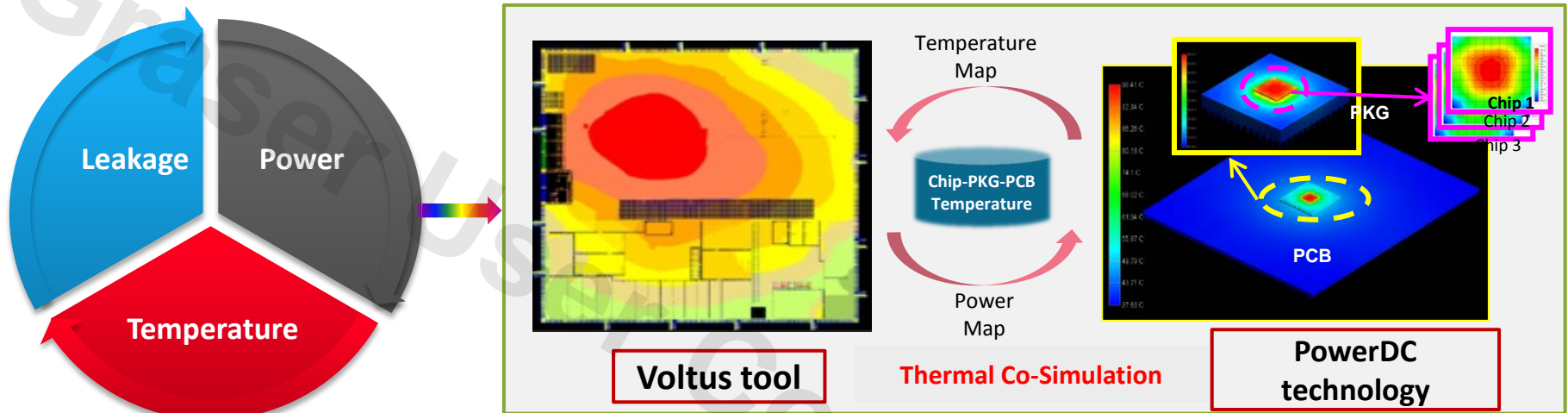
Chip/package/board co-analysis



- **Sigrity package model generation**
 - XtractIM™ broadband SPICE format
 - PowerSI® S-parameter format
- **Voltus™ die model generation**
 - Broadband SPICE format
 - Frequency and time domains
 - Single-port and N-port (up to 100s)
- **Sigrity MCP interface**
 - Model connection protocol
 - Name- or location-based
- **Complete power integrity solutions**
 - Chip: Voltus solution + package model
 - System: PowerDC™ technology + die model

Complete solutions

Electrical/thermal co-analysis



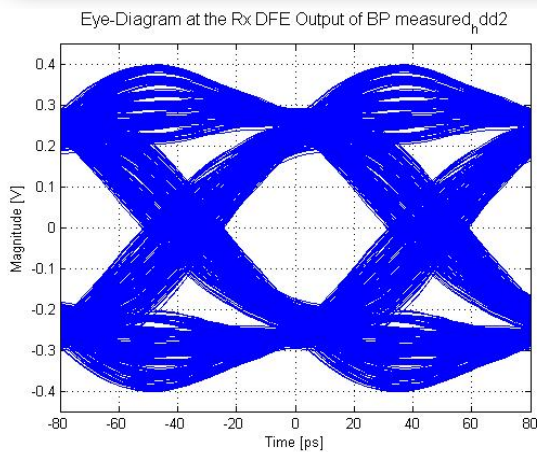
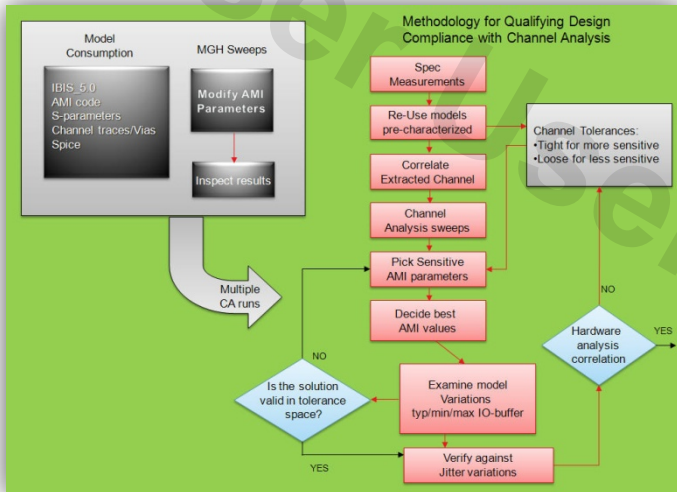
- Thermal runaway
 - Positive feedback among chip's temperature, leakage, and power dissipation
 - Temperature-dependent IR-drop and EM
- Thermal simulation in "Voltus tool + PowerDC technology"
 - Voltus output: temperature and location-dependent "power map" file
 - PowerDC technology computes detailed temperature distribution for chip-PKG-PCB (T vs. time)
 - Voltus tool reads back "temperature map" file for EMIR convergence
 - Thermal view available in 2D/3D

Complete solutions

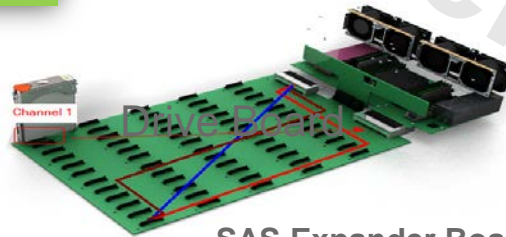
A success story

2011 DesignCon

12Gbps shown feasible



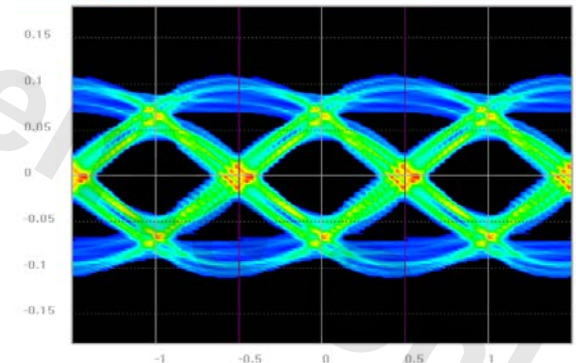
2012 Sigrity Acquisition



SAS Expander Board

2014 CDNLive

12Gbps confirmed



| | Simulated | Measured | Hspice |
|------------|-----------|----------|--------|
| eye height | 80mv | 78mv | 83 |
| eye width | 56ps | 58ps | 61 |

Summary

From Geometry-based layout check to Level-3 simulation-based layout check

From Mainstream level-1 SI simulation to Level-3 power-aware SI simulation

From Parallel bus simulation to Serial link simulation

From PDN DC simulation to PDN AC simulation to Decap optimization

From Electrical simulation to Electrical / Thermal co-simulation

From SI simulation to PI simulation to SI/PI/EMI co-simulation

From IOSSO / PDN PCB level simulation to Chip/Pkg/Board co-simulation

From Pkg electrical model generation to Thermal pkg parameters generation

From BBS model extraction to RFIC passive component extraction

From IBIS model generation to AMI model generation

SPEED2000 PowerSI 3D-EM

SystemSI T2B PowerDC

Broadband SPICE OptimizePI

XtractIM OrCAD PCB SI

XcitePI IO-SSO solution

Allegro Sigrity SI Base + options

Allegro Sigrity PI Base + options

Cadence/Sigrity
is
your single stop
SI/PI/EMI solutions
for
chip-package-board
analysis

Single-stop SI/PI solution for chip-package-board

cā dence[®]